




Surface Patterning of MEMS-Related Materials

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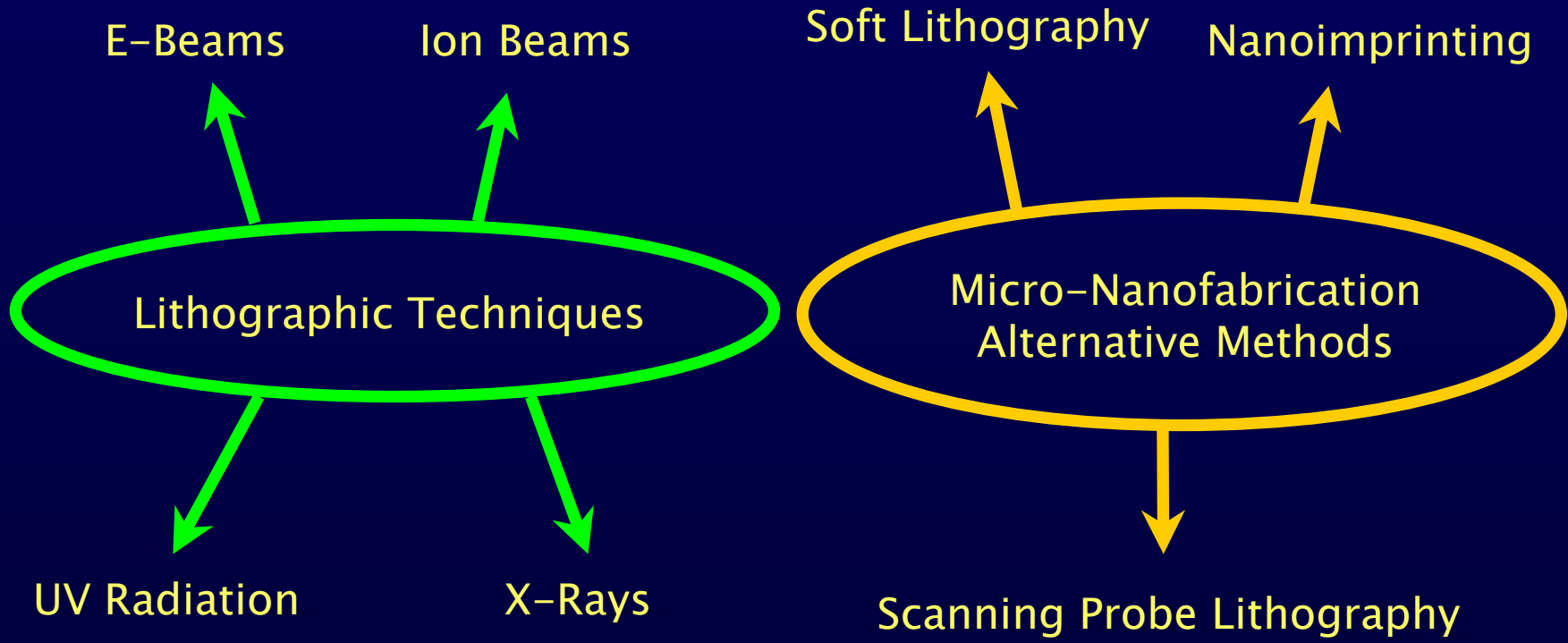
Why is it so important to achieve an accurate control of the patterned topography of a material?

A large, hollow, downward-pointing arrow with a stepped profile, connecting the top box to the middle box.

**Mechanical and Electromechanical Devices
Microcutting Tools
Stamps for Nanoimprinting
Optoelectronic Devices**

A large, hollow, upward-pointing arrow with a stepped profile, connecting the bottom box to the middle box.

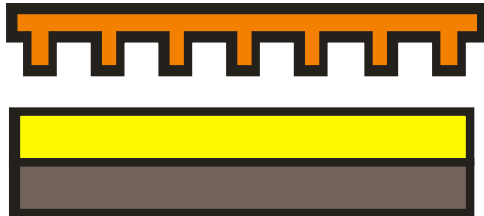
Applications of Patterned Surfaces of Diverse Materials



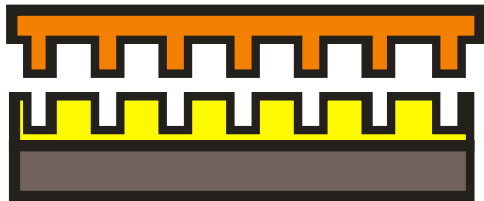
Some alternative patterning methods:

- Scanning Probe Microscopy
- Metastable Ions
- Femtosecond laser pulses
- Laser-focused deposition
- Laser-assisted direct imprinting
- Soft Lithography

PDMS stamp

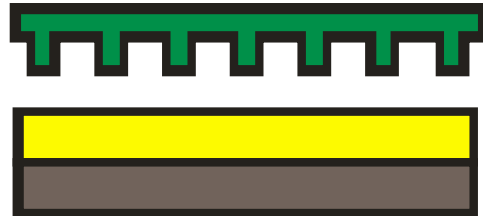


Prepolymer + Pressure

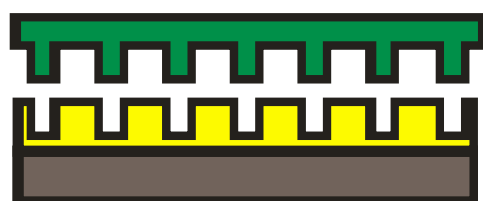


Soft Lithography

Silicon stamp

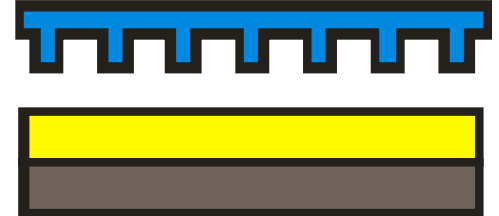


Polymer + Heat + Pressure

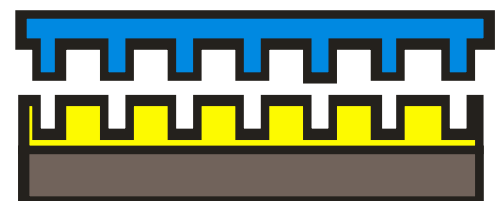
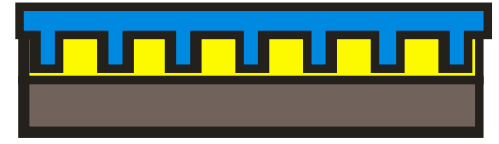


**Nanoimprint
Lithography**

Quartz stamp



Prepolymer + UV Radiation



**Step and Flash
Lithography**

Soft Lithographic Techniques

Replica Molding

Microtransfer Molding

Micromolding in Capillaries

Solvent-Assisted Micromolding

Microcontact Printing

Nanotransfer Printing

Nanoimprint Lithography

Step and Flash Imprint Lithography

**SOFT LITHOGRAPHIC
TECHNIQUES**



PDMS, Silicon & Quartz Stamps



**Surface Patterning of
Polymeric Materials**



Non-Conductive Stamps



**Pressure, Heat
and/or UV-Radiation**



Conductive Stamps

**Applied Potential at the
Electrode-Electrolyte Interface**



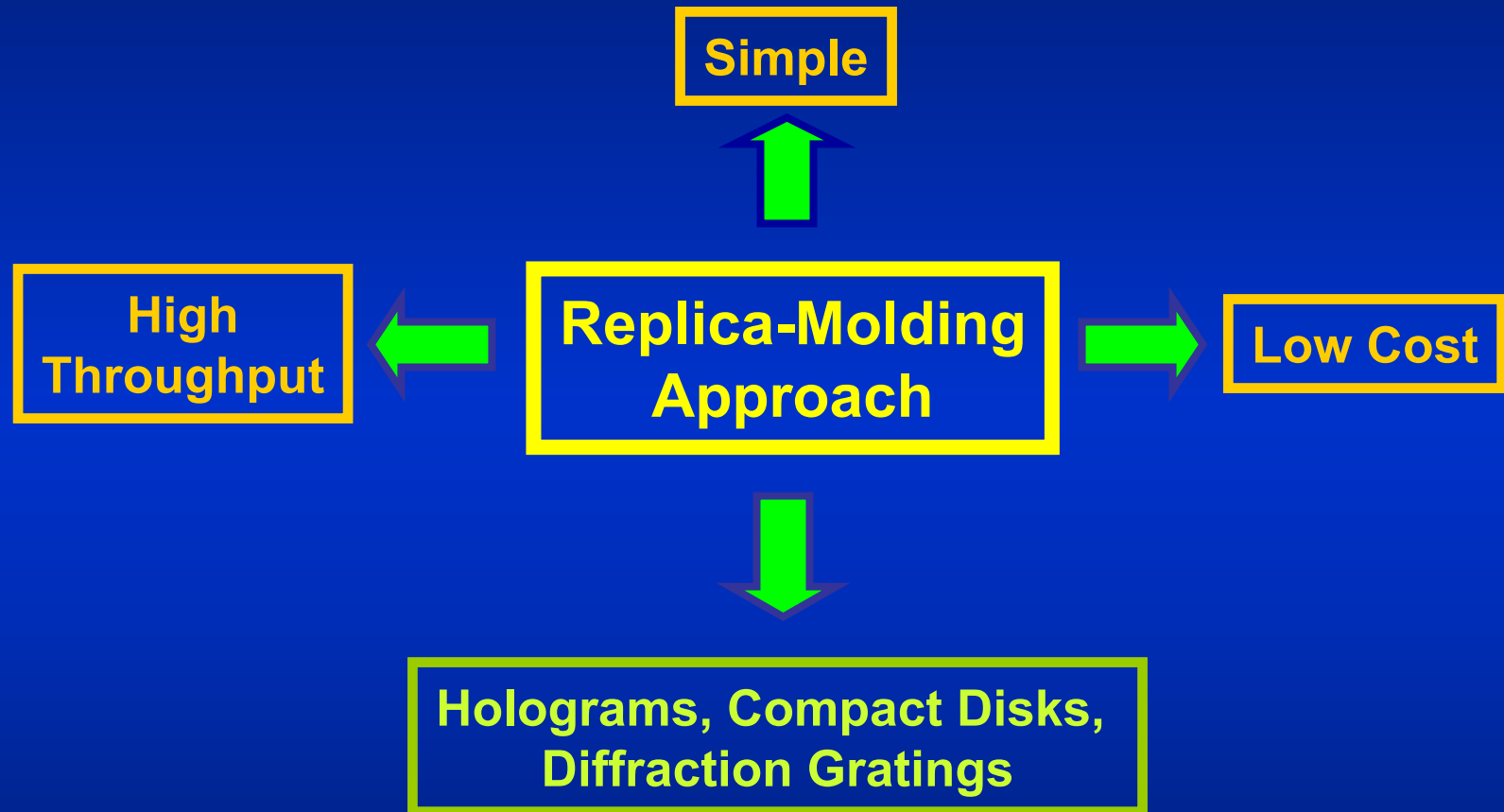
**“ELECTROCHEMICAL”
SOFT LITHOGRAPHY**



**Direct Surface Patterning of Metals,
Alloys, Semiconductors**



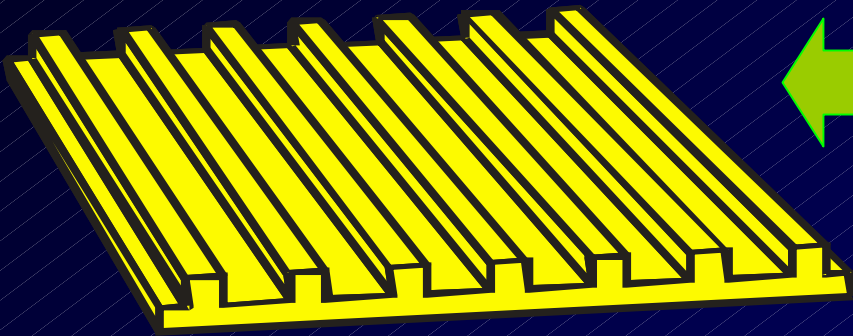
Molding Strategies...Why?



SURFACE-CHEMISTRY RELATED PROBLEMS

**DIRECT ELECTROCHEMICAL DEPOSITION
ONTO THE METALLIC STAMP**

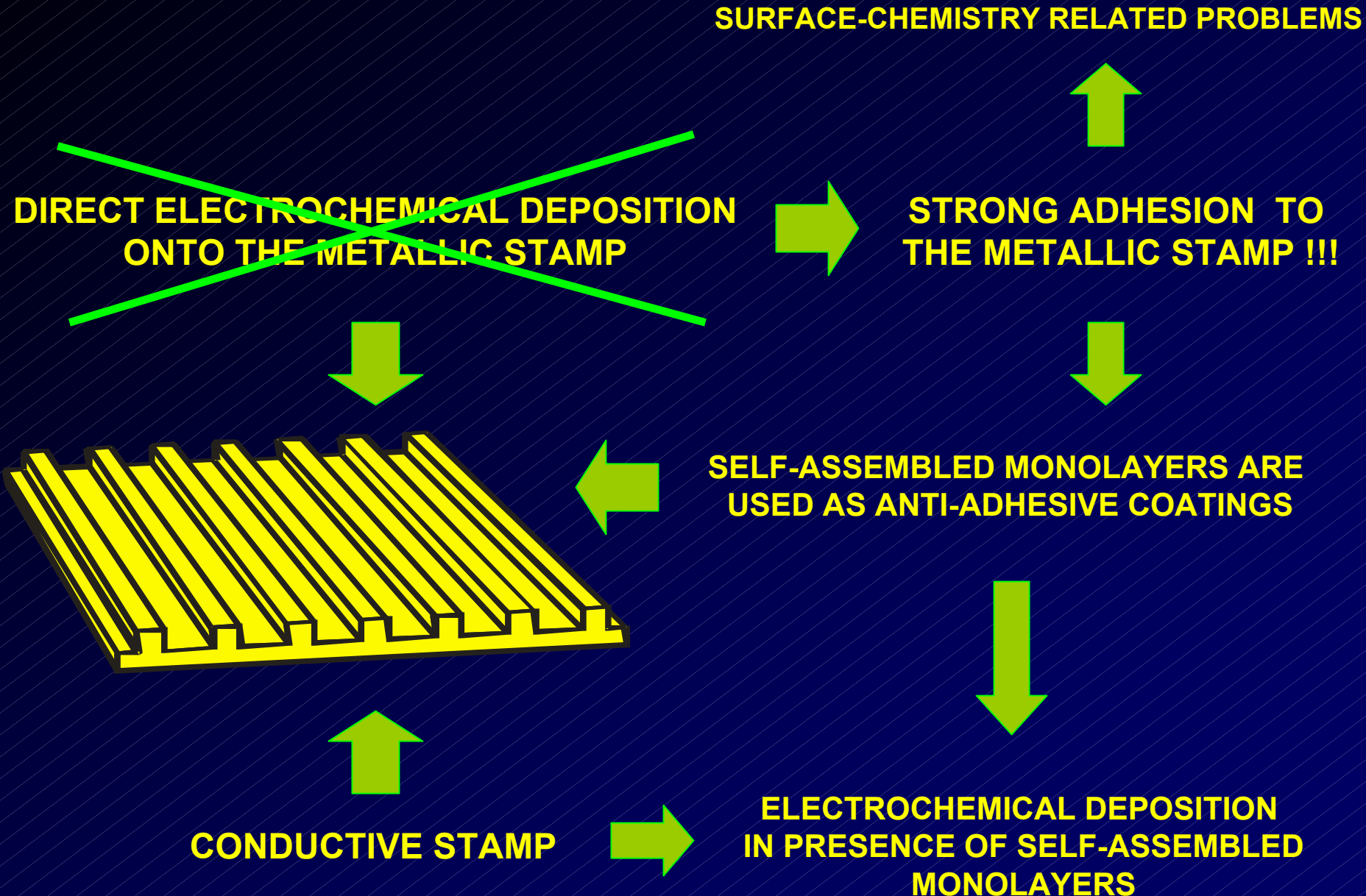
**STRONG ADHESION TO
THE METALLIC STAMP !!!**



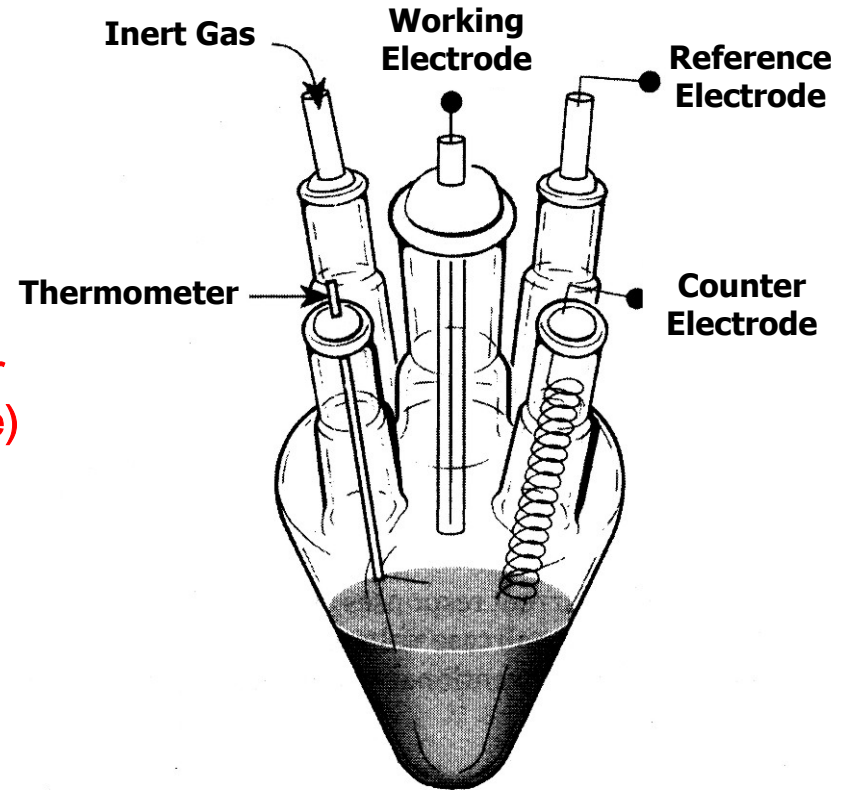
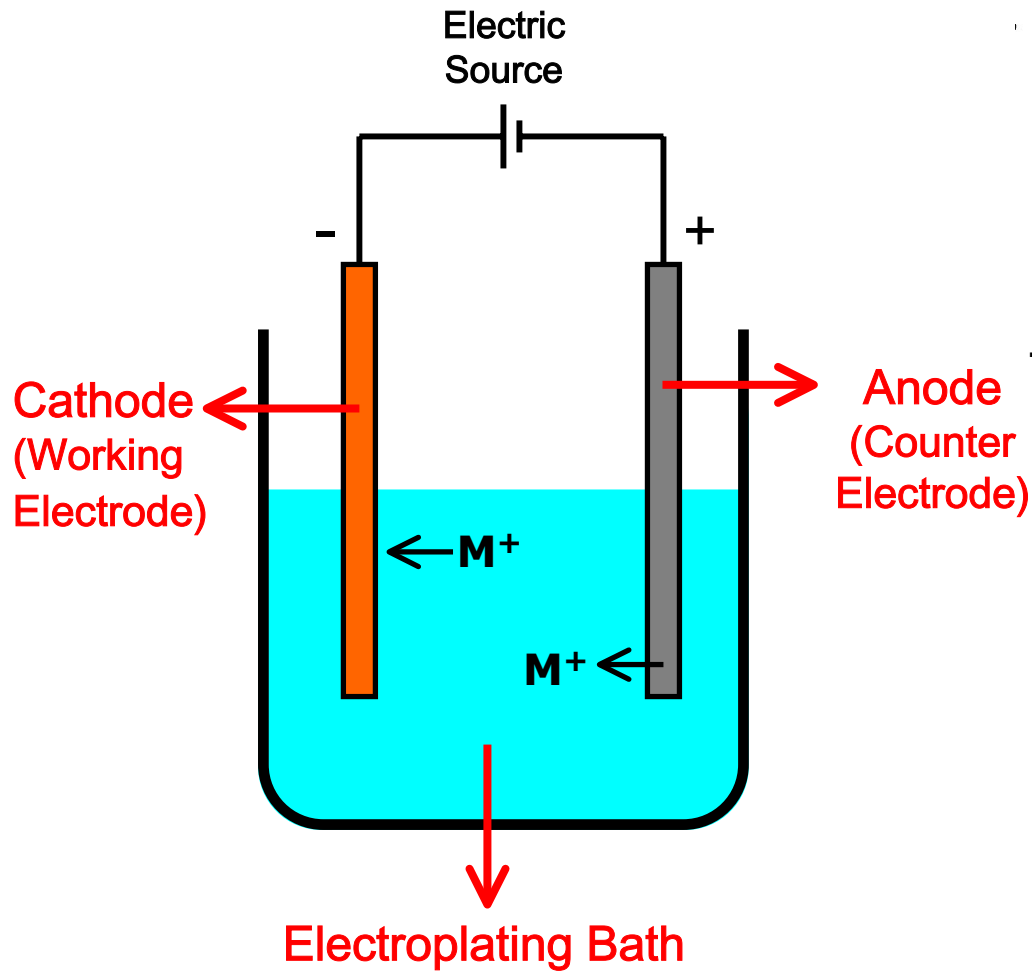
**SELF-ASSEMBLED MONOLAYERS ARE
USED AS ANTI-ADHESIVE COATINGS**

CONDUCTIVE STAMP

**ELECTROCHEMICAL DEPOSITION
IN PRESENCE OF SELF-ASSEMBLED
MONOLAYERS**

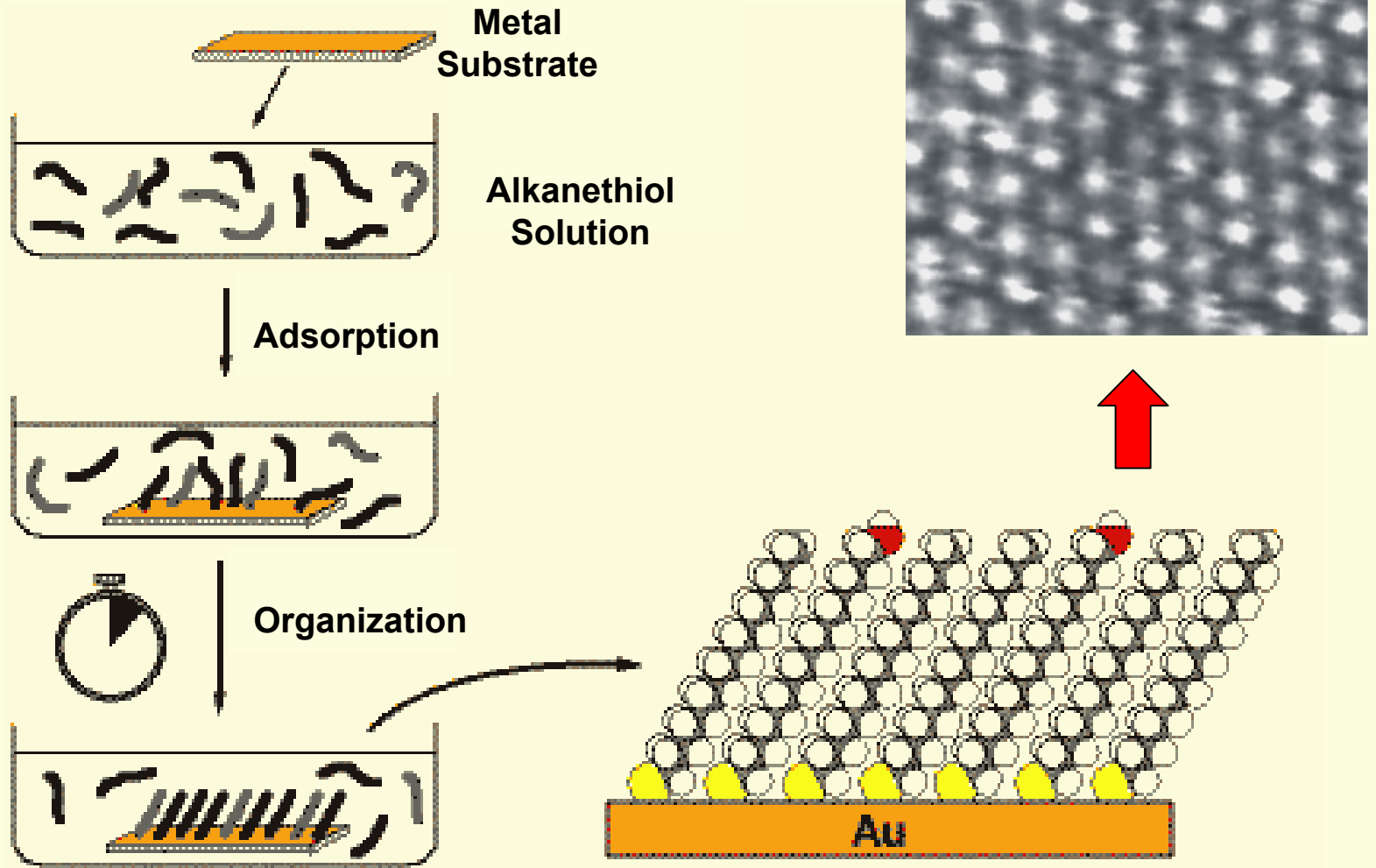


Electrochemical Deposition - Electroplating

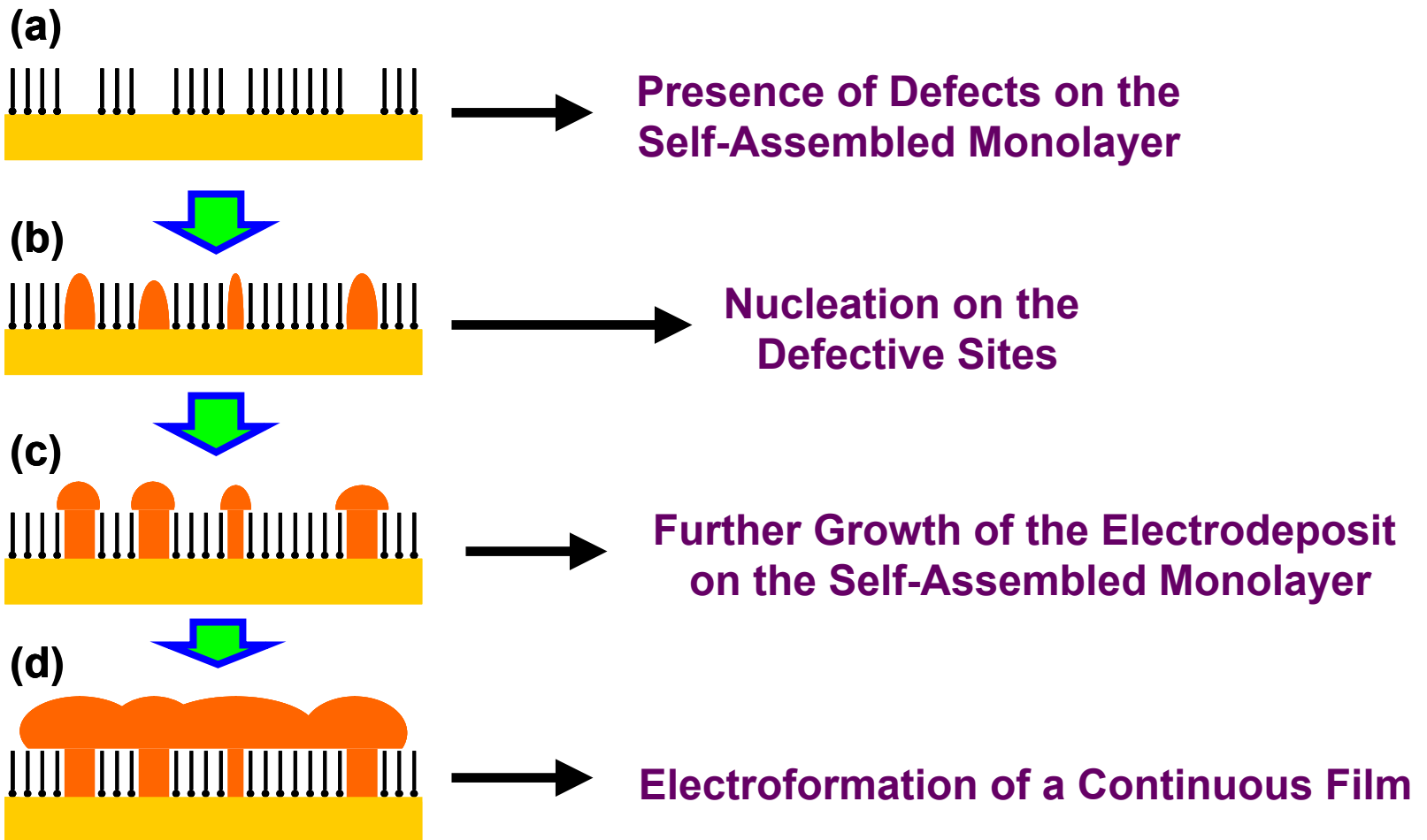


Conventional Electrochemical Cell

Molecular Self-Assembly of Alkanethiols on Metal Surfaces

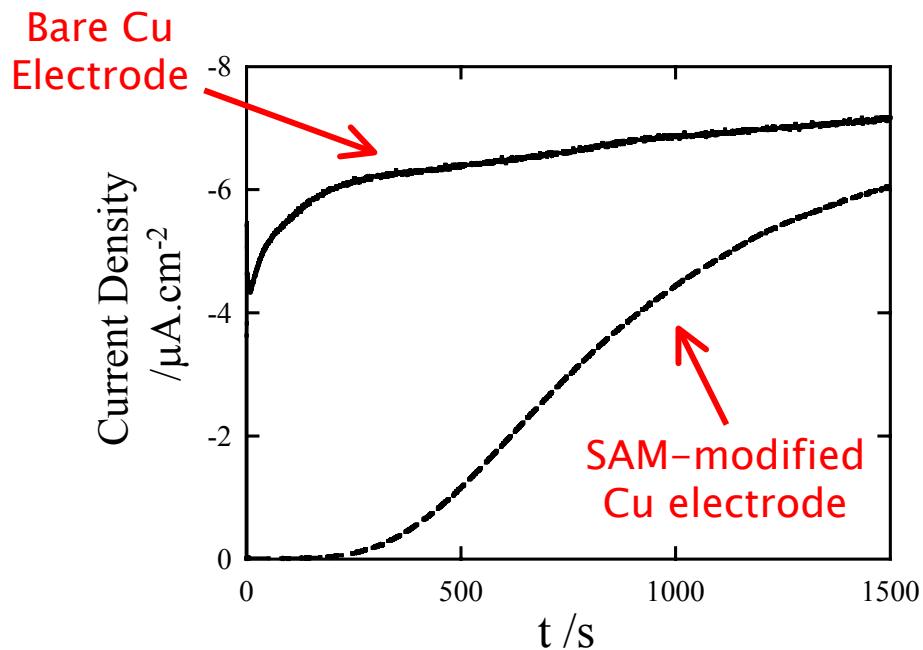


Mechanism of Electrodeposition onto SAMs



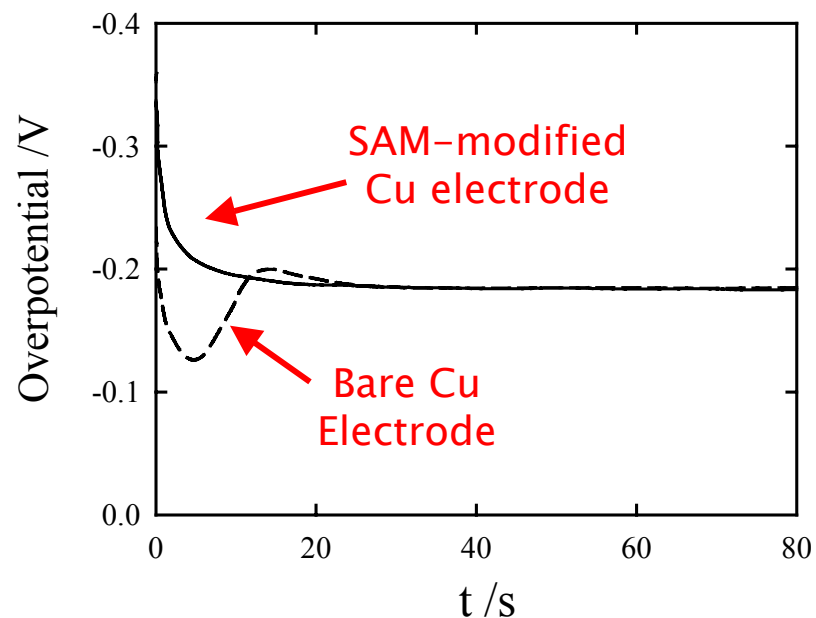
Metal Electrodeposition onto Self-Assembled Monolayers

Potential-Controlled Electrodeposition



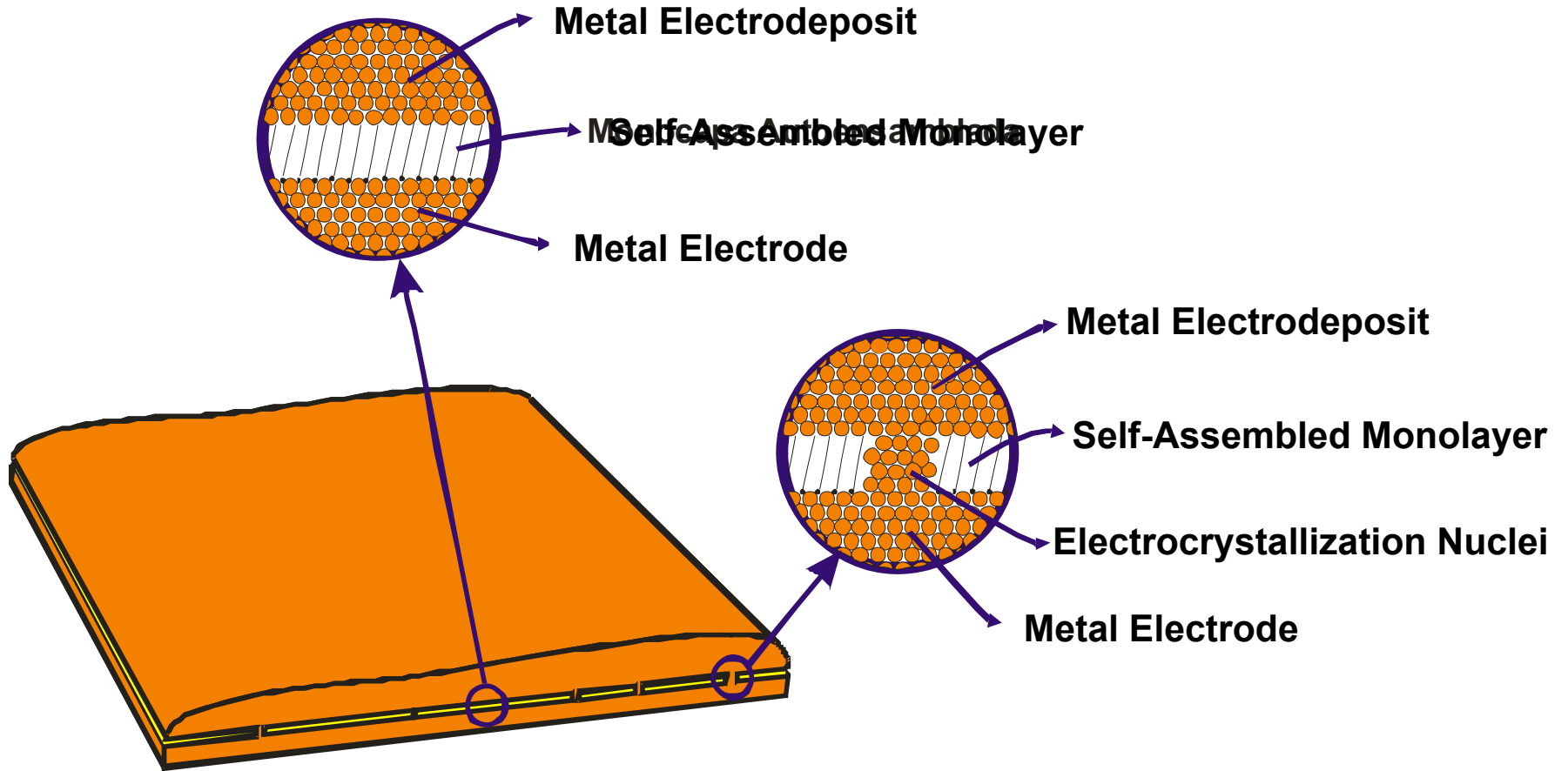
$\eta = -90\text{mV}$
Electrolyte: $\text{CuSO}_4\cdot 5\text{H}_2\text{O}$ 0,6 M + H_2SO_4 0,5 M

Current-Controlled Electrodeposition

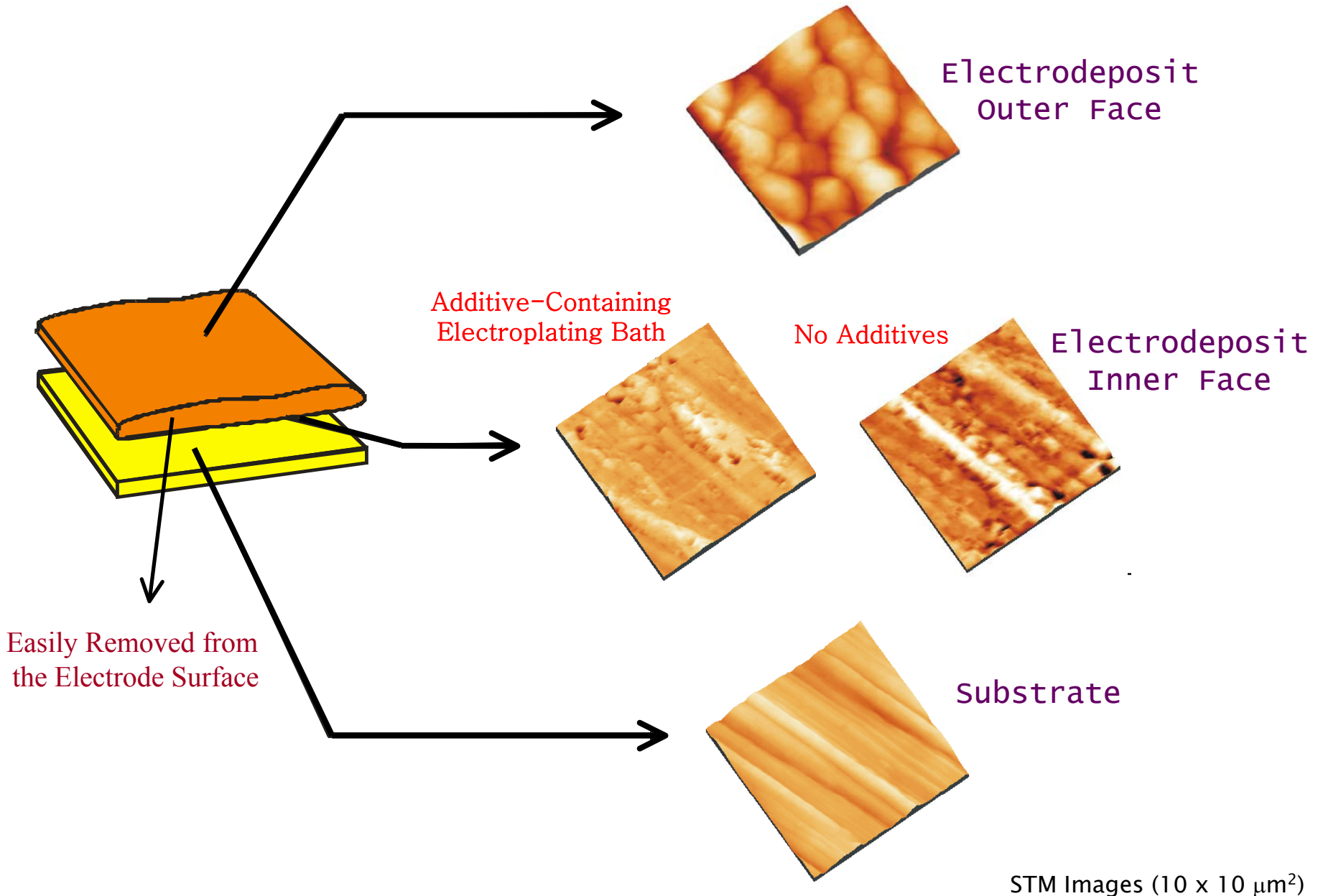


$j = -20 \text{ mA}\cdot\text{cm}^{-2}$
Electrolyte: $\text{CuSO}_4\cdot 5\text{H}_2\text{O}$ 0,6 M + H_2SO_4 0,5 M

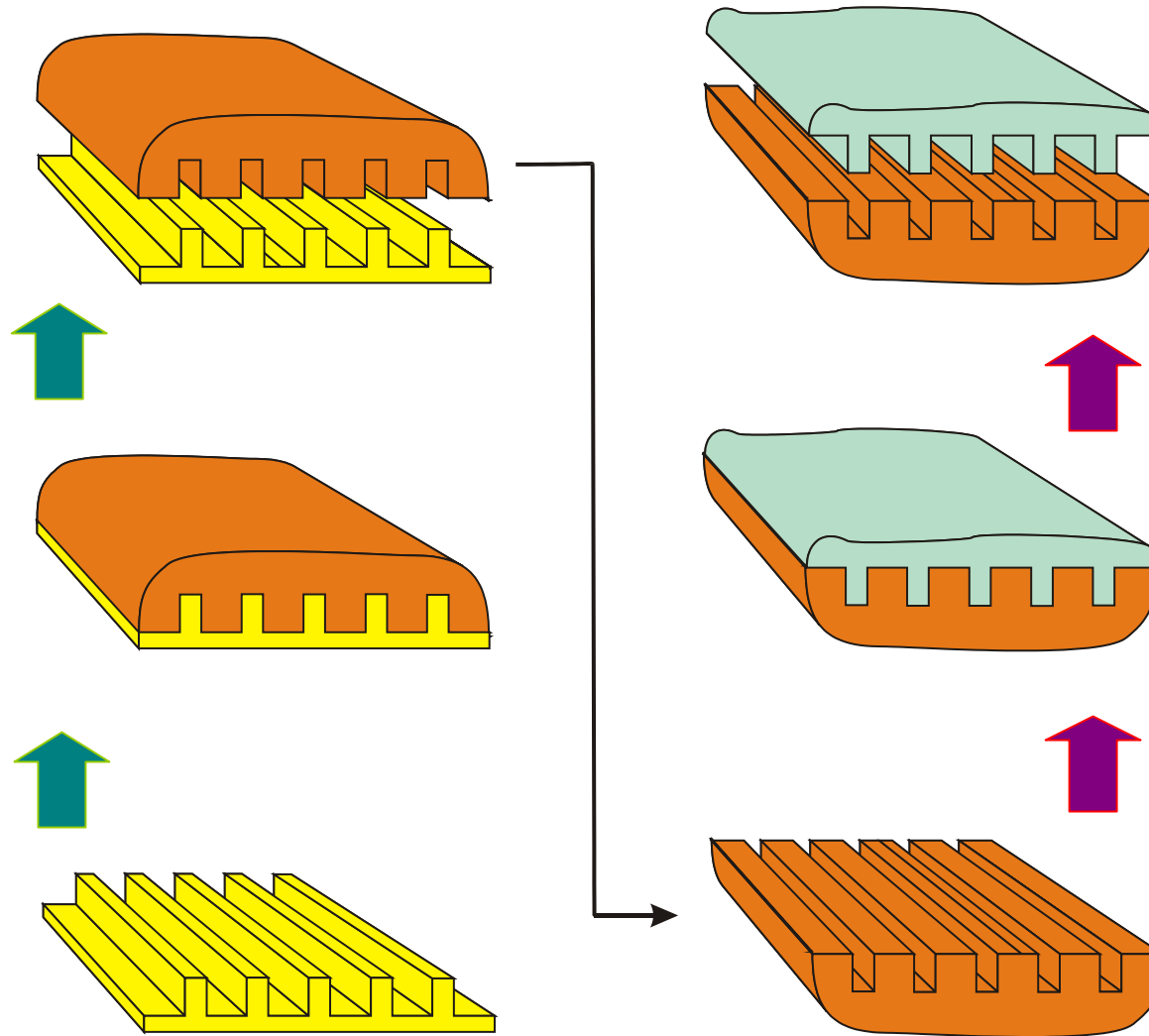
Electrodeposit-SAM-Electrode Interface



Adhesive Properties of the Electrodeposits in Presence of SAMs

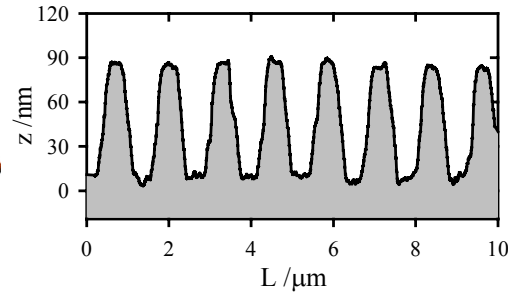
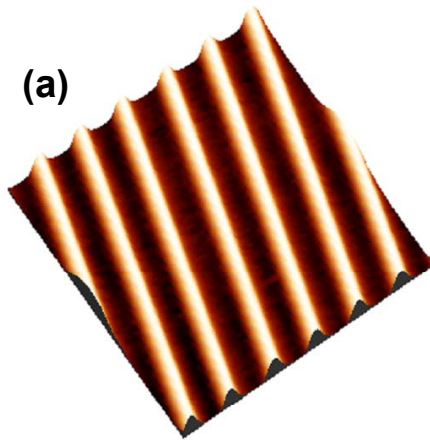


Electrochemical Replica-Molding



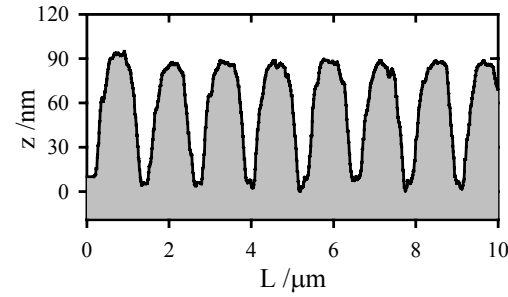
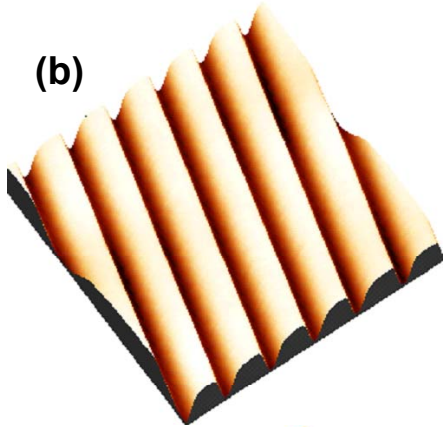
Current-Controlled Cu Electrodeposition

(a)



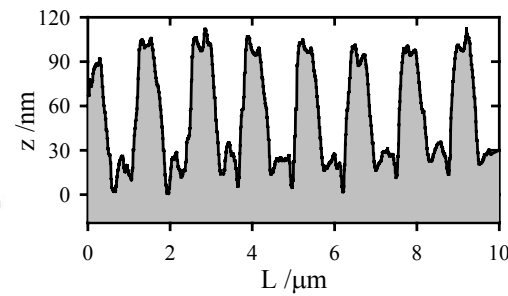
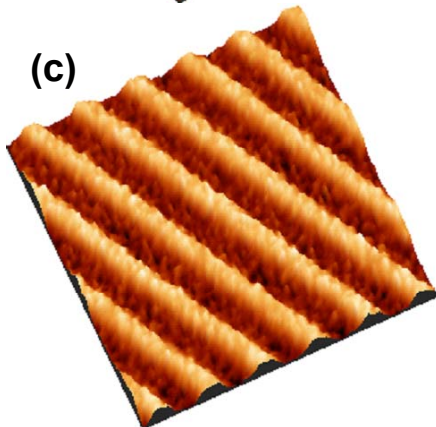
Cu
Stamp

(b)



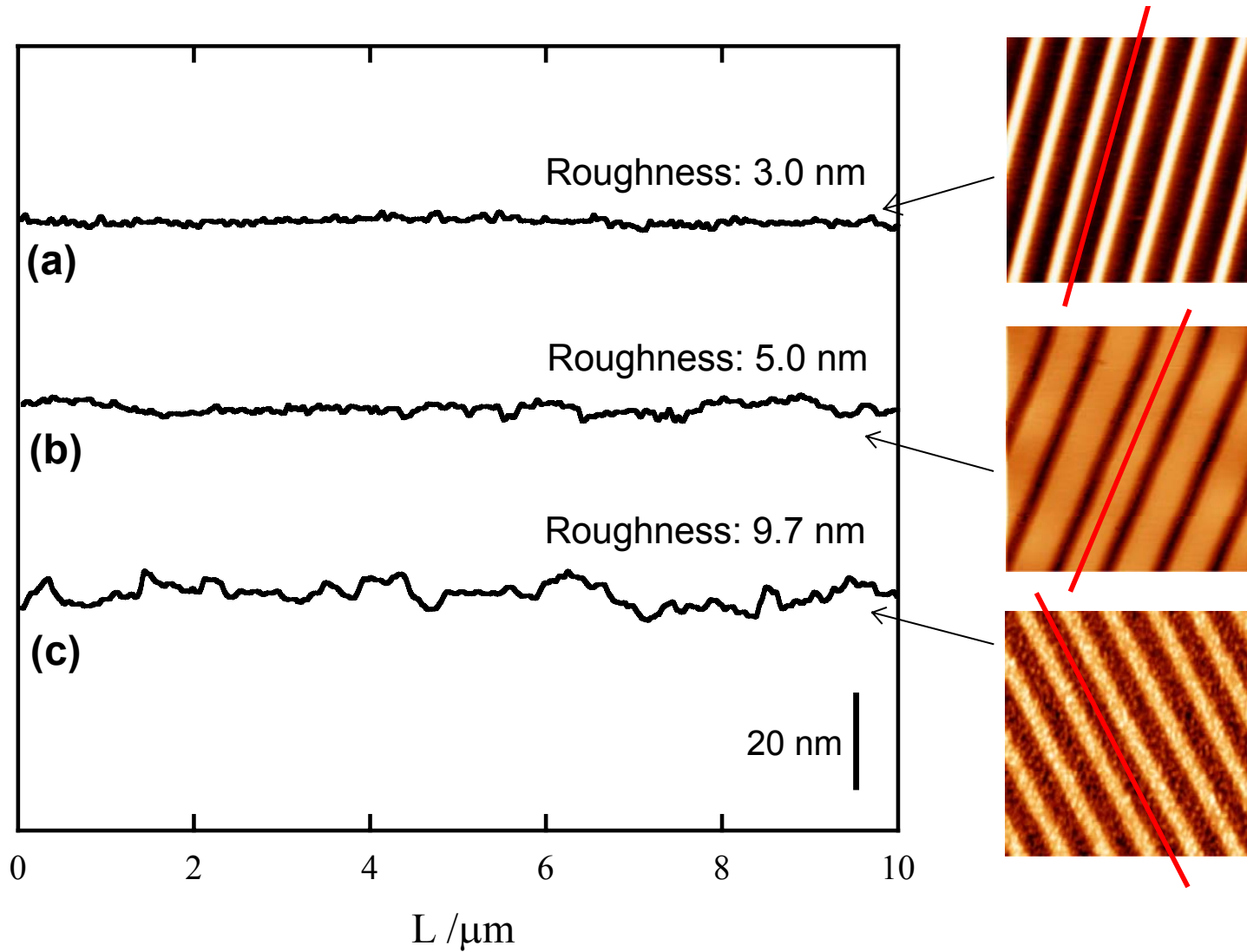
Molded Cu
Surface

(c)



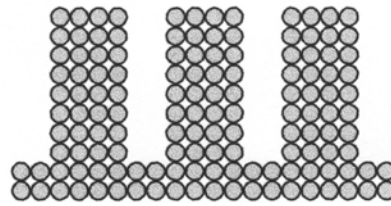
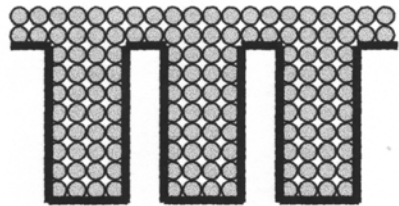
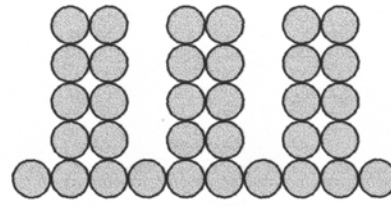
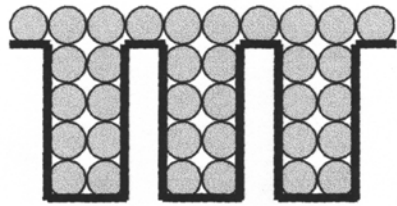
Replicated Cu
Surface

Electrochemical Replica-Molding Roughness Analysis

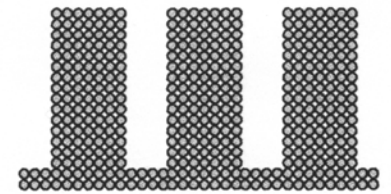
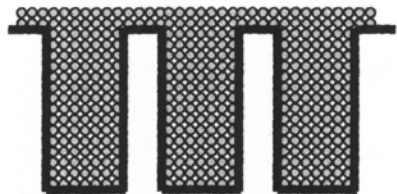


Electrochemical Replica-Molding at the Microscale

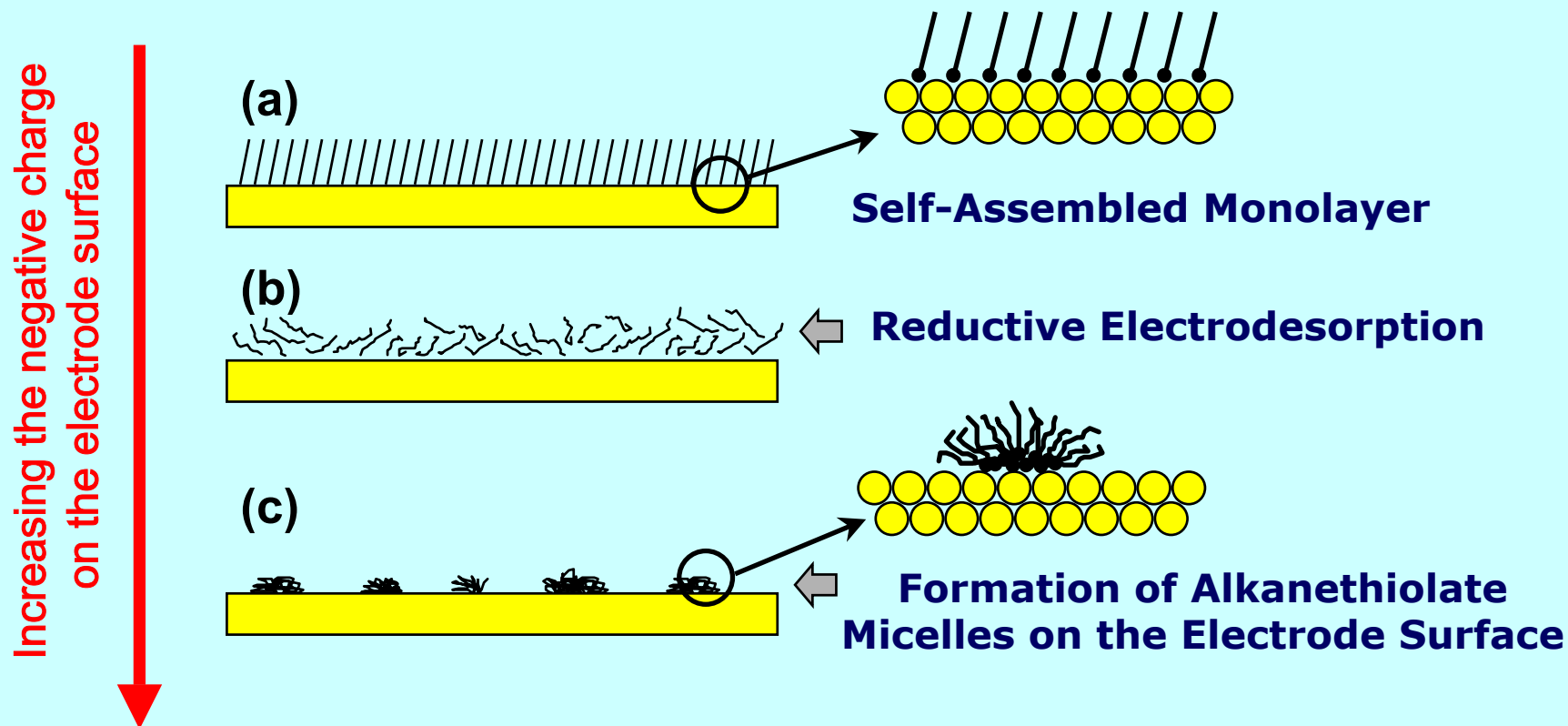
Grain Size Effects



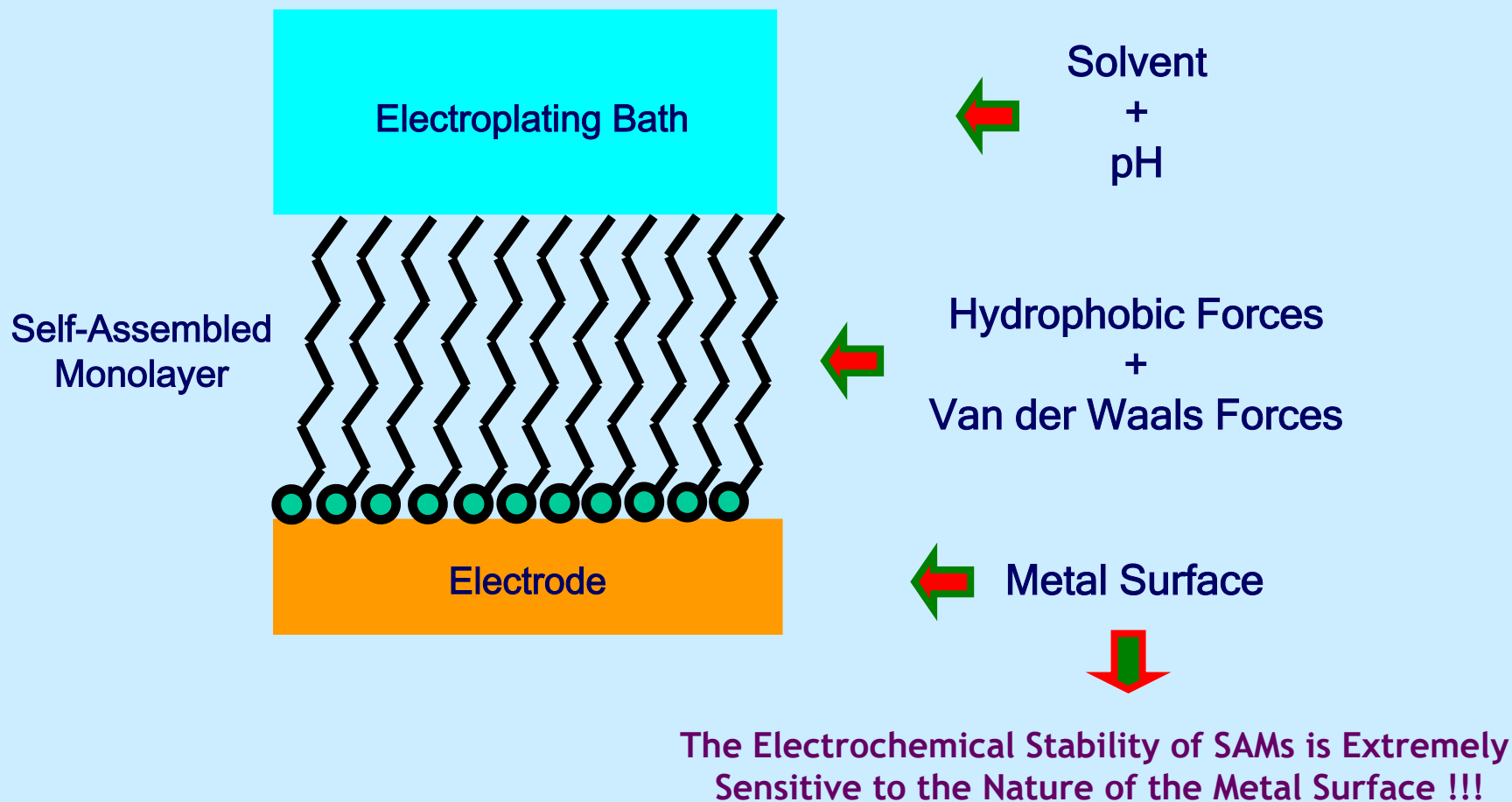
**Grain Size and Smoothness
Can Be Controlled by
Adding Organic Additives
to the Electroplating Bath**



Electrochemical Stability of the Self-Assembled Monolayer at the Electrode-Electrolyte Interface



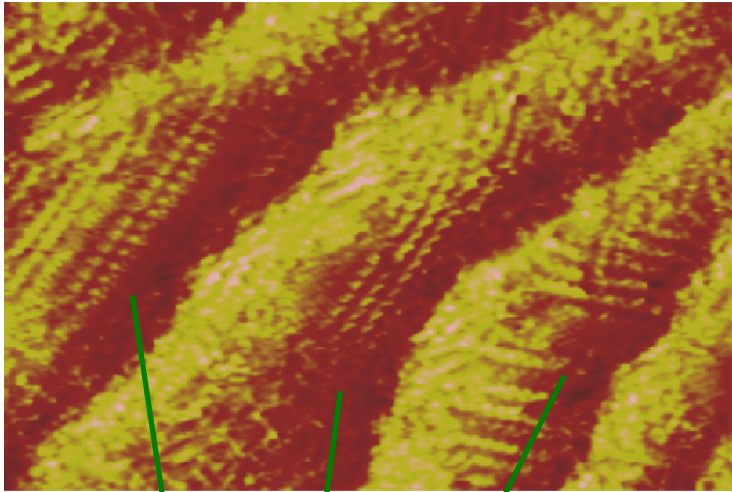
Main factors ruling the stability of SAMs in electrochemical environments



Electrochemical Micromolding → Electrodeposition of Nickel

(a)

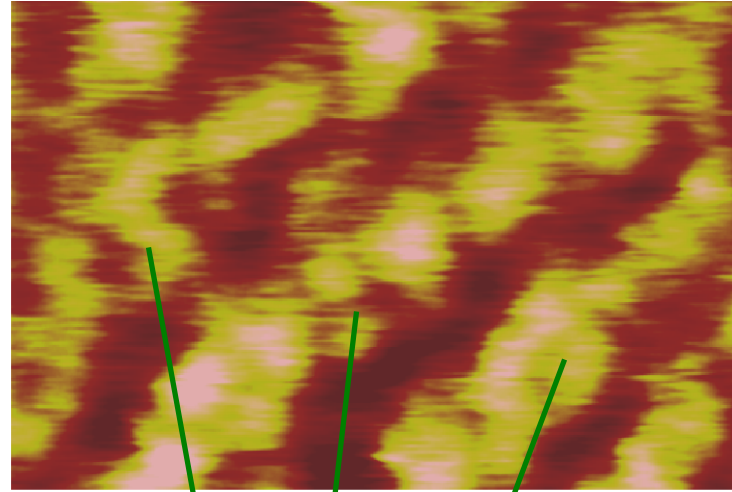
-200mV



Alkanethiolate Monolayer
Self-Assembled onto the Au Surface

(b)

-490mV

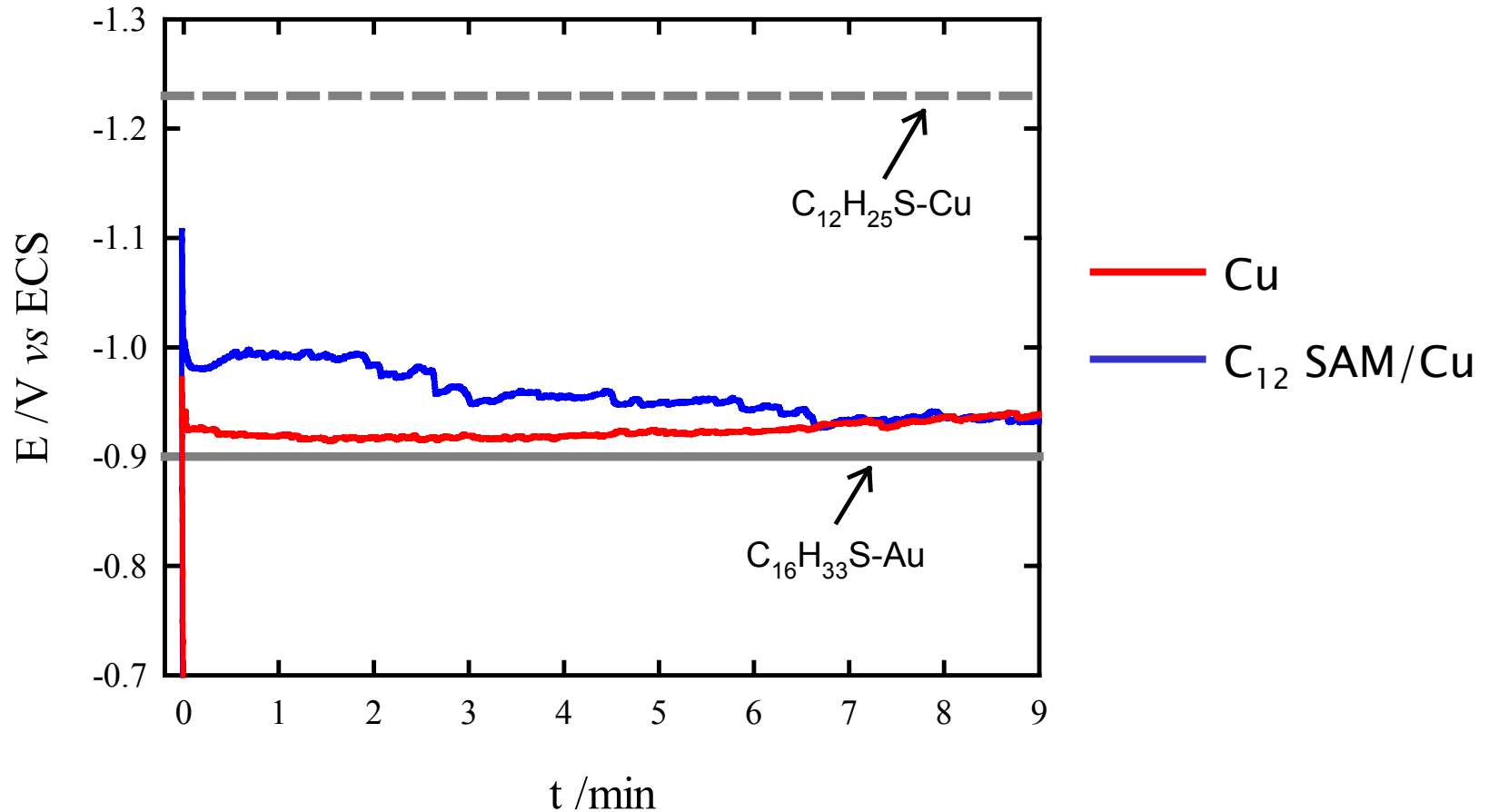


Formation of Alkanethiolate
Micelles on the Au Surface

No Evidence
of Nickel
By AES !!!

EC-STM images (25 x 40 nm²). All the potentials are referred to the SCE. Hexanethiolate-modified Au(111).
Electrolyte: NiSO₄·7H₂O 1,14M + NiCl₂·6H₂O 0,25M + H₃BO₃ 0,61M (pH = 2).

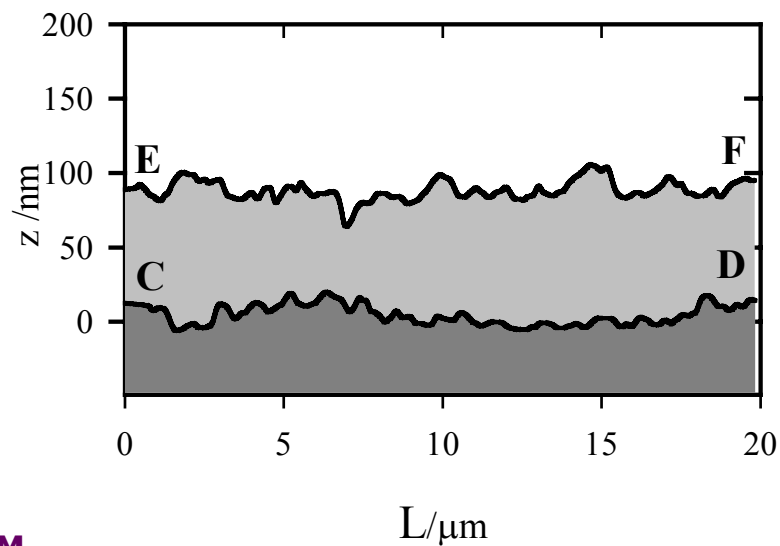
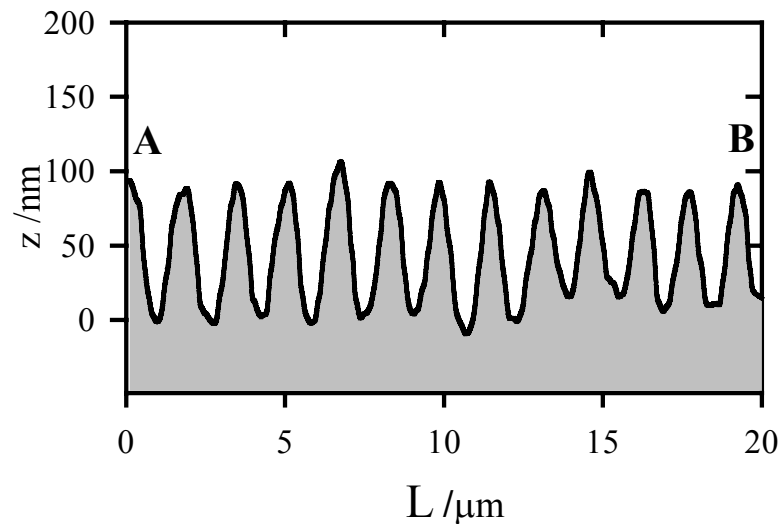
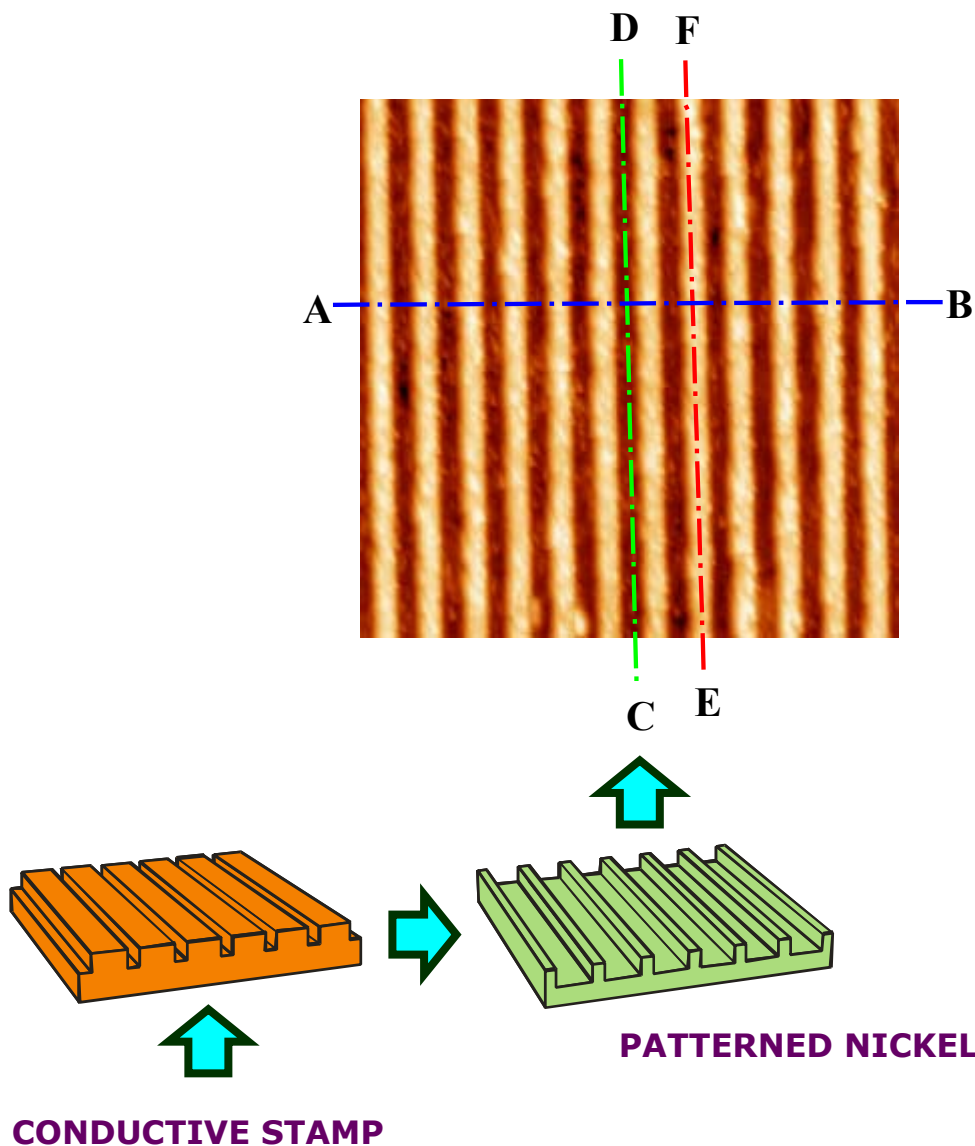
Current-Controlled Nickel Electrodeposition onto SAM-Modified Metal Stamps



$$j = -40 \text{ mA}\cdot\text{cm}^{-2}$$

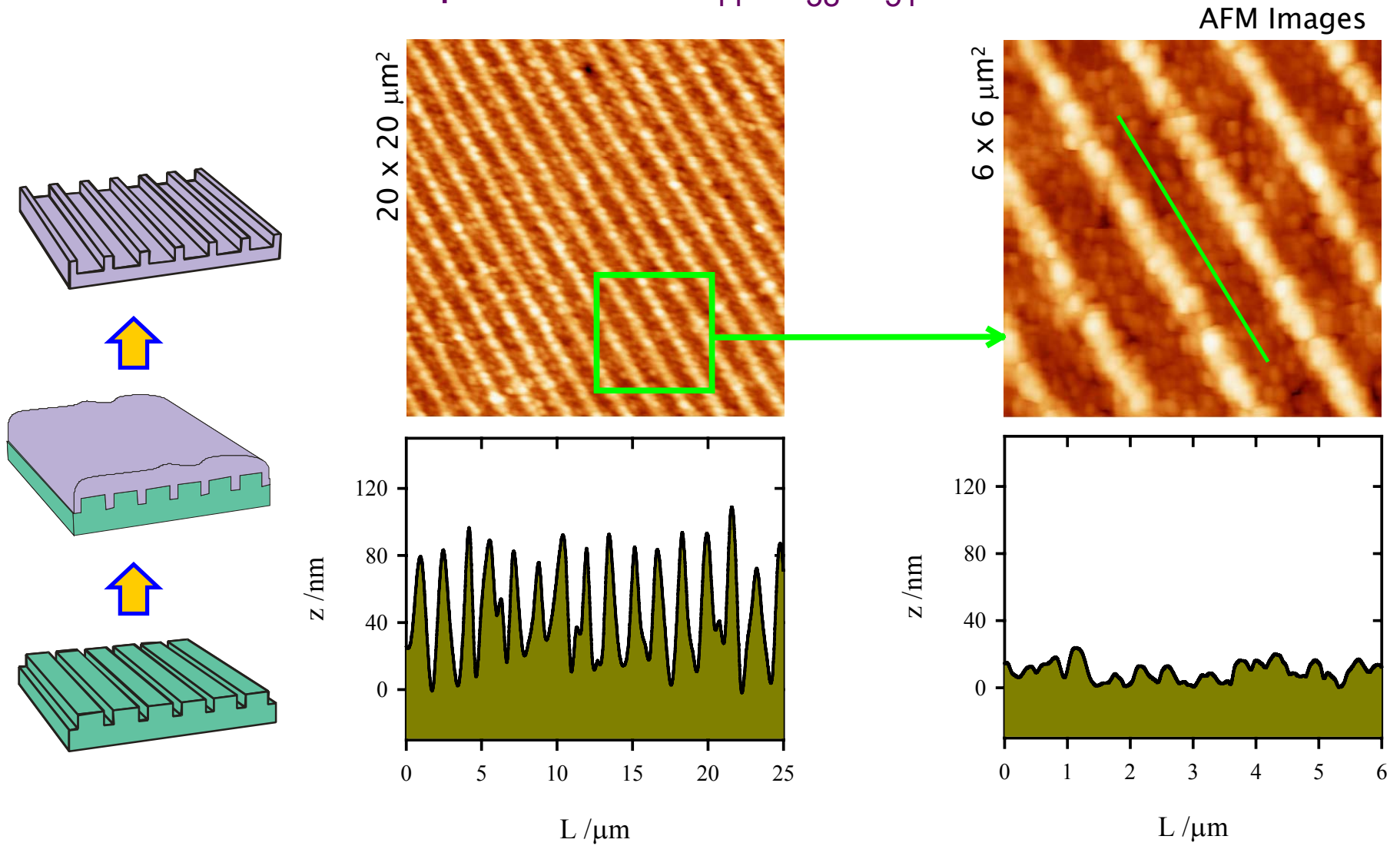
Electrolyte: $\text{NiSO}_4\cdot 7\text{H}_2\text{O}$ 1,14M + $\text{NiCl}_2\cdot 6\text{H}_2\text{O}$ 0,25M + H_3BO_3 0,61M. $T = 326$ K

Relief-Transfer on Nickel Films by Direct Electrochemical Micromolding



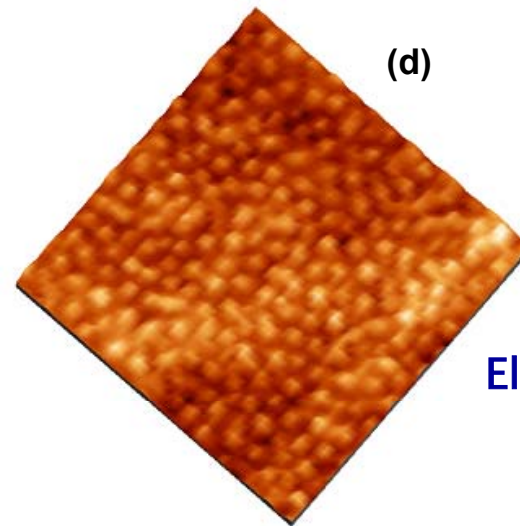
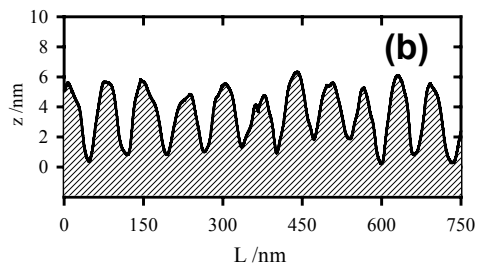
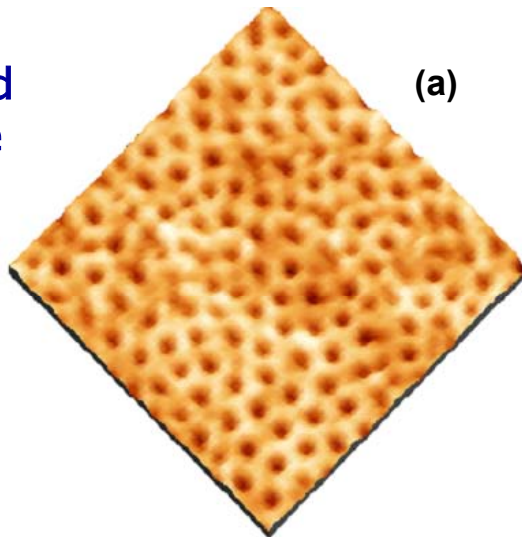
AFM Image ($20 \times 20 \mu\text{m}^2$)

Surface Patterned Bulk Ternary Alloy Electrochemical Deposition of $\text{Fe}_{11}\text{Co}_{38}\text{Ni}_{51}$

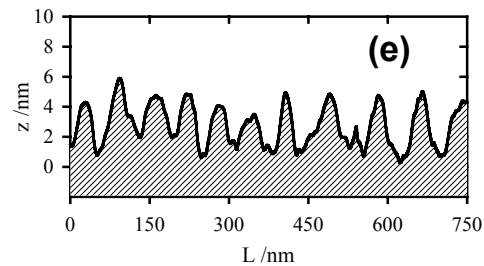


Downsizing the patterning scale Electrochemical Nanomolding → Cu Electrodeposition

SAM-modified
Nanostructured
Gold Electrode



Electrochemically-
Nanomolded
Cu Surface



AFM Images (800 x 800 nm²)

**“ELECTROCHEMICAL”
SOFT LITHOGRAPHY**



**Surface-Relief Transfer by Electrochemical
Deposition onto SAM-Modified Stamps**



**Direct Surface Patterning
of Bulk Metal Oxides
by an Electrochemical Route**

**Surface Patterning of
Bulk Metals and Alloys**



Zinc Oxide (ZnO)

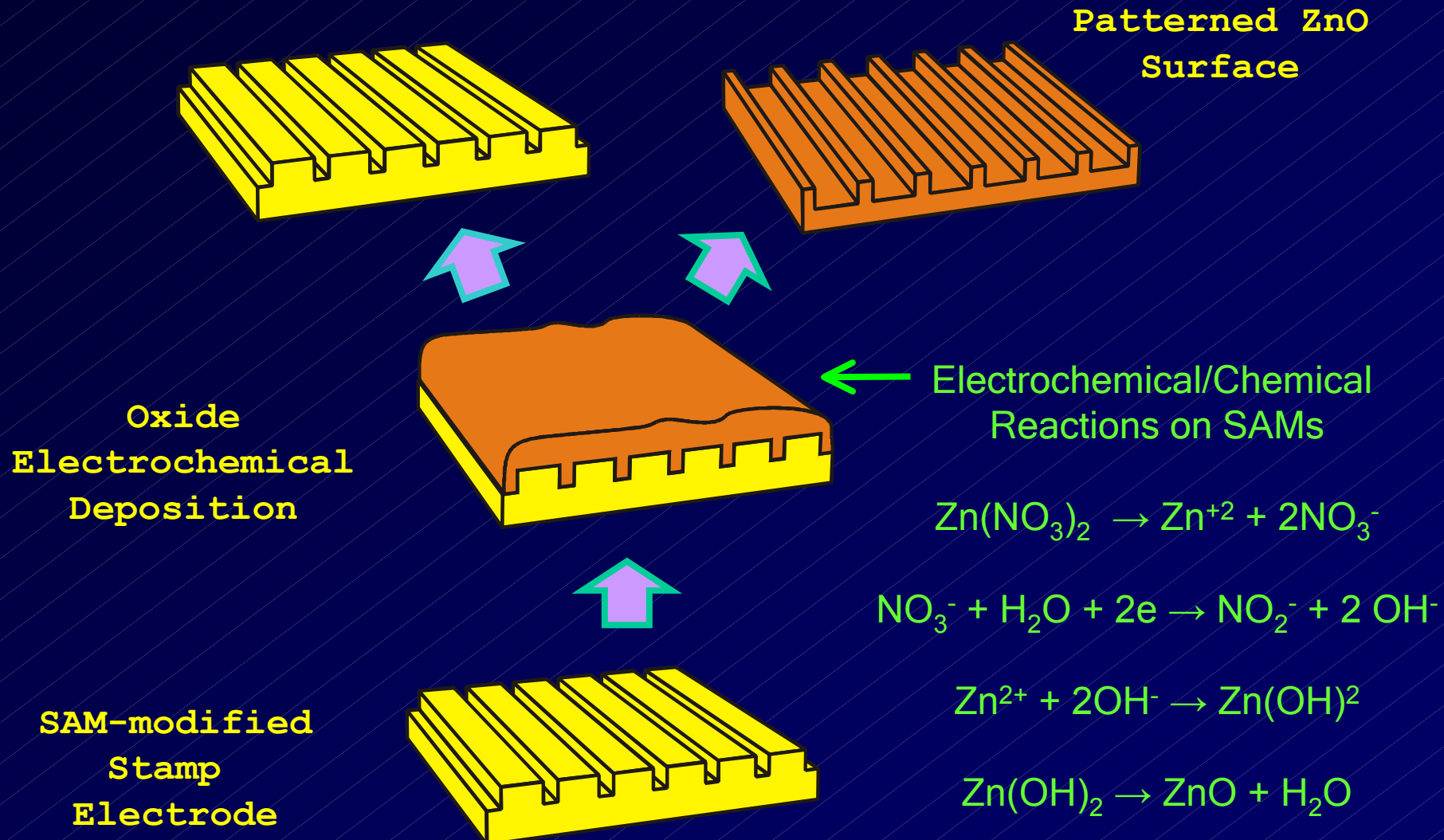


**Several Metal Oxides Can Be
Electrodeposited Without Damaging
the Self-Assembled Monolayer**



MEMS, solar cells and others

Surface Patterning of Metal Oxides by "Electrochemical" Soft Lithography



Copper Stamp

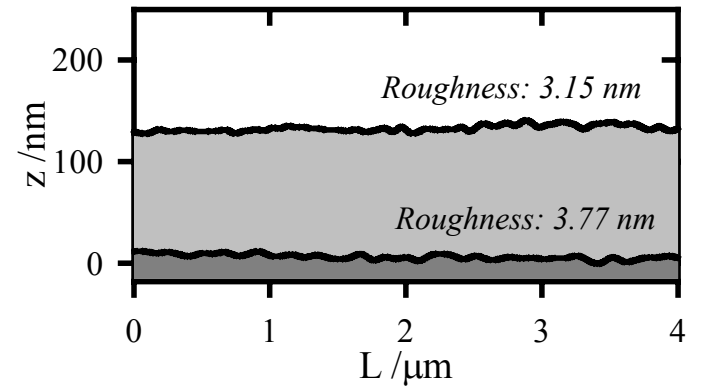
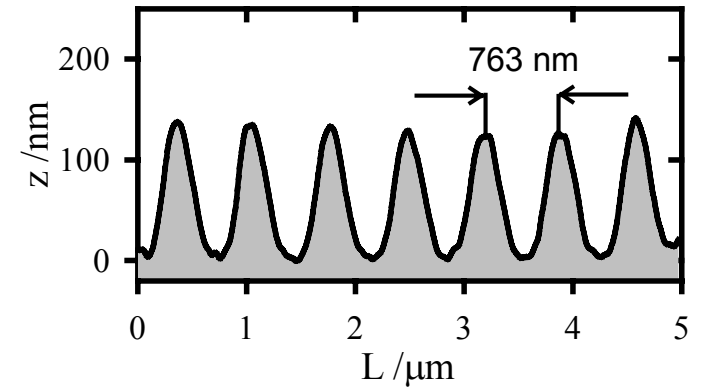
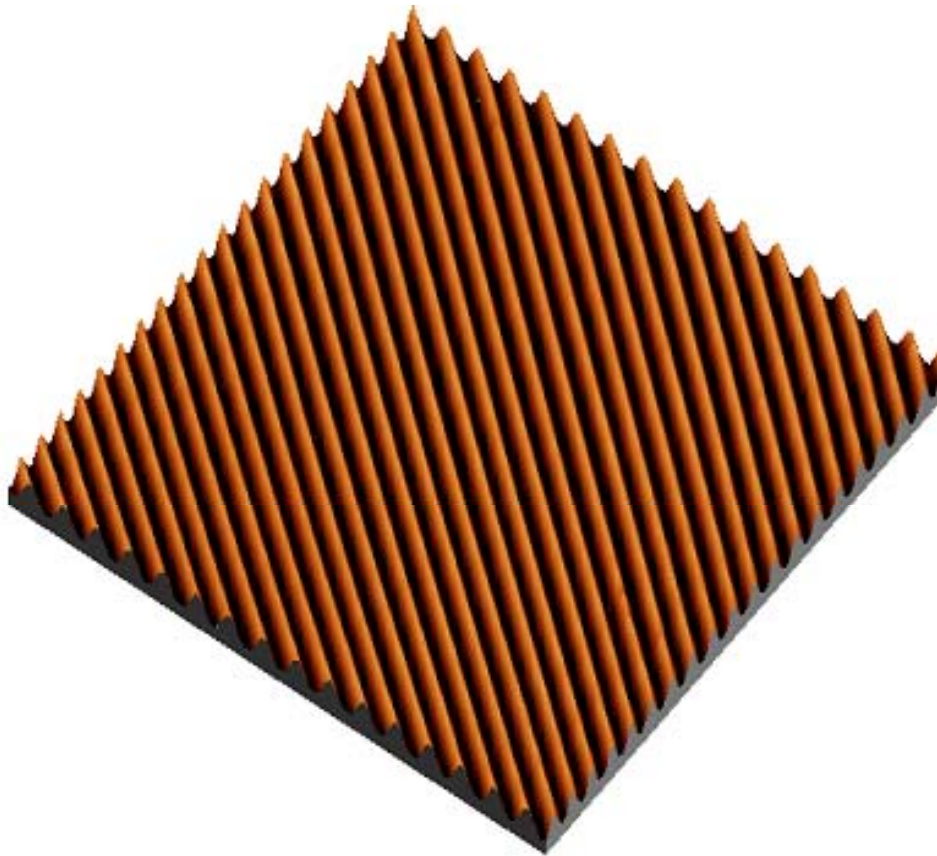
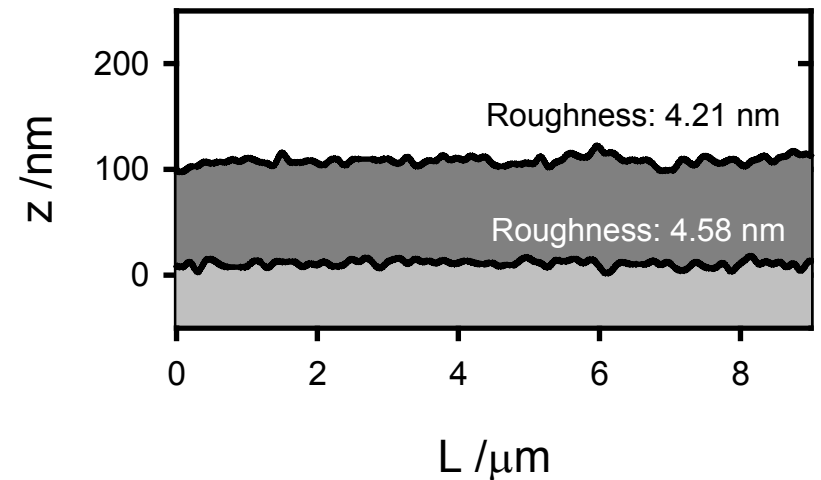
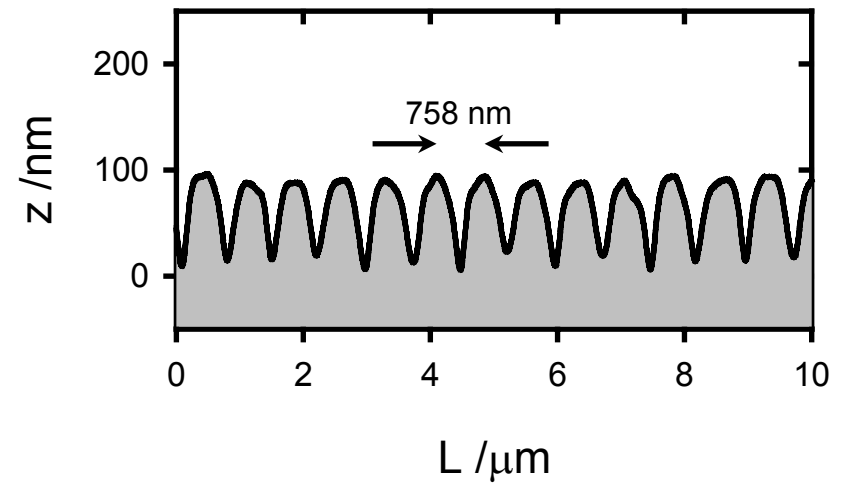


Imagen AFM ($20 \times 20 \mu\text{m}^2$)

Patterned Zinc Oxide (ZnO) Surface Micromolded by “Electrochemical” Soft Lithography



AFM Image ($9 \times 9 \mu\text{m}^2$)

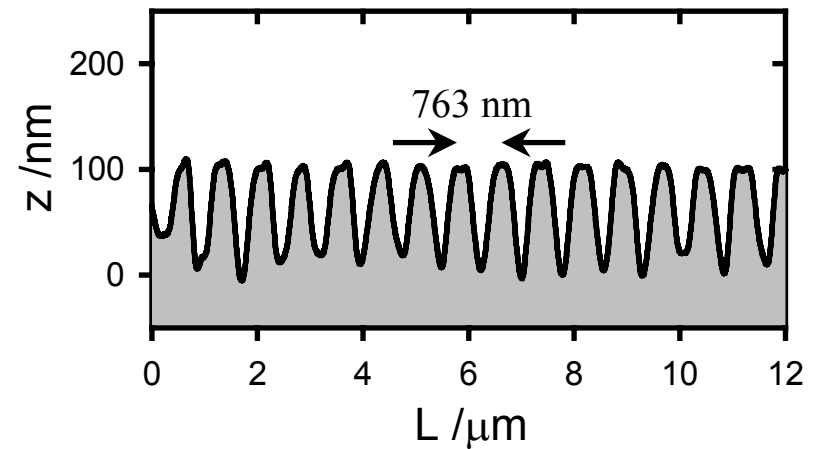
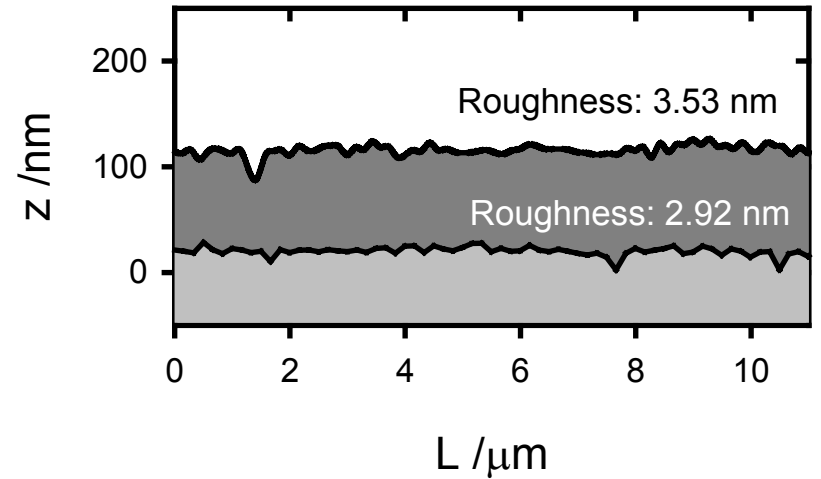


“Electrochemical” Soft Lithography – Metal Oxides

Surface Patterned Bulk Cuprous Oxide (Cu_2O)



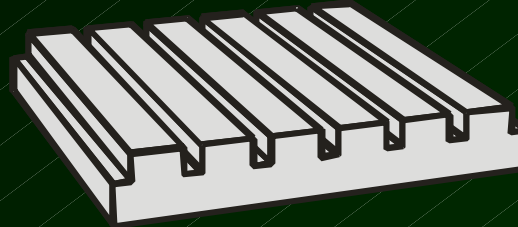
AFM Image ($12 \times 12 \mu\text{m}^2$)



SOFT LITHOGRAPHIC TECHNIQUES



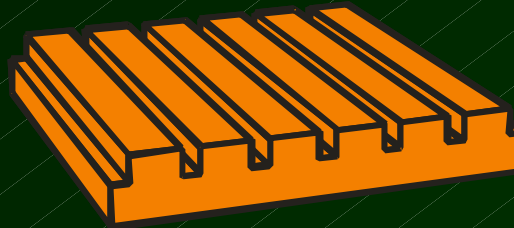
Non-Conductive Stamps



**PDMS,
Silicon
or Quartz**



Conductive Stamps



Metal



**“ELECTROCHEMICAL”
SOFT LITHOGRAPHY**

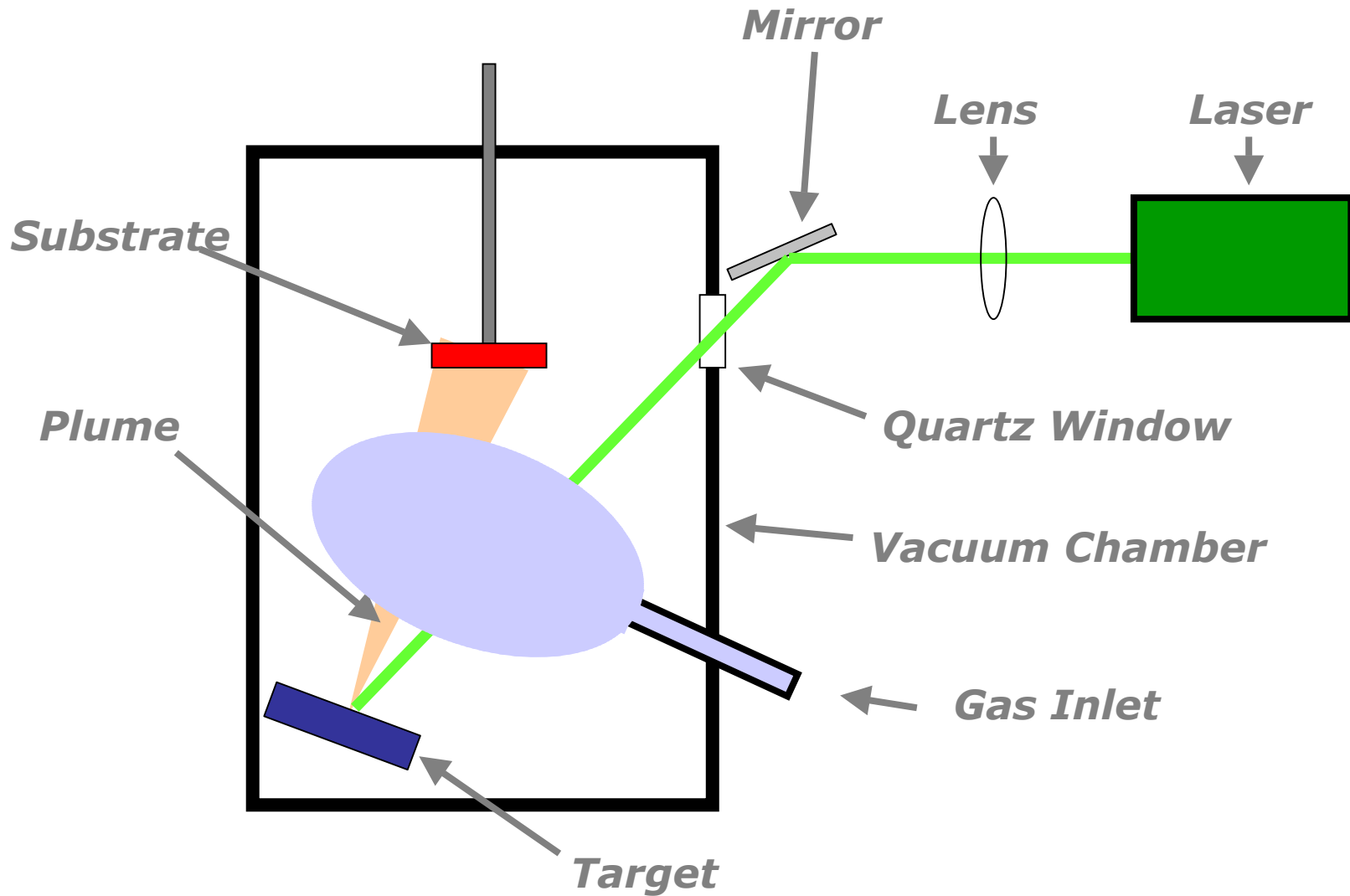


**Direct Surface Patterning of
Metals, Alloys, Semiconductors**



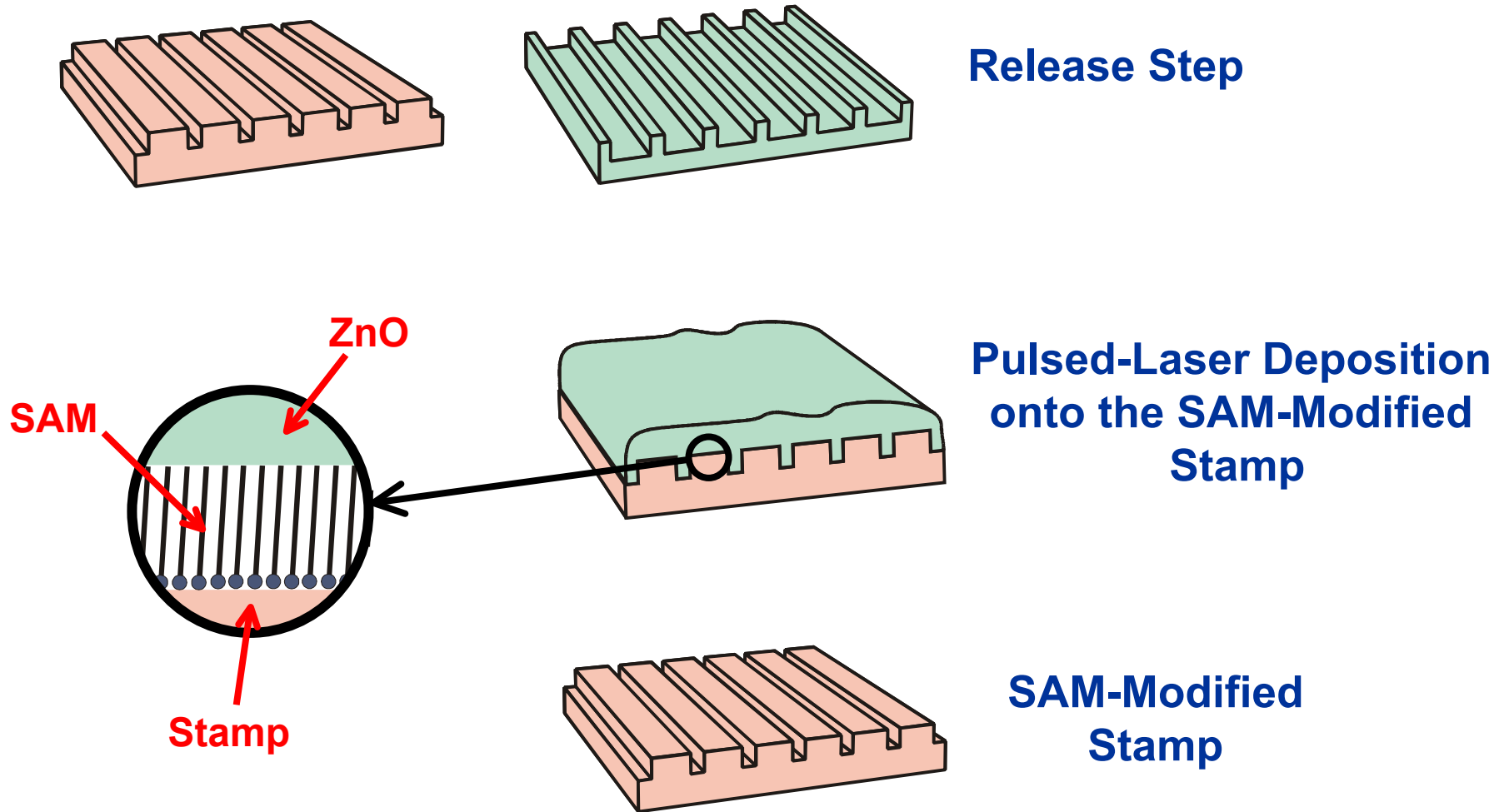
Is it possible to the use SAM-modified metallic stamps in combination with other deposition techniques different from the electrodeposition?

Pulsed-Laser Deposition of Zinc Oxide (ZnO) Films



Dr. Carlos Zaldo – Department of Ferroelectric Materials
Instituto de Ciencia de Materiales de Madrid (Spain)

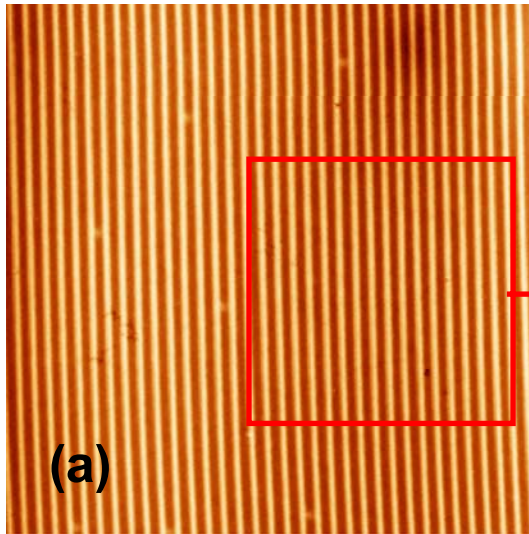
Molding Surface-Relief Patterns on ZnO Surfaces Deposited by Pulsed-Laser Ablation



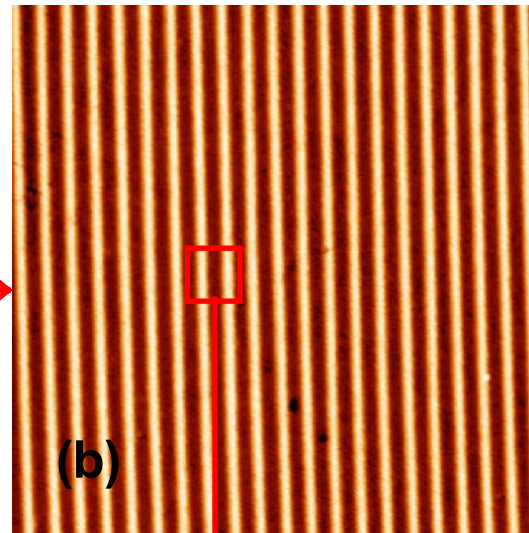
Patterned Zinc Oxide (ZnO) Surfaces

AFM Images

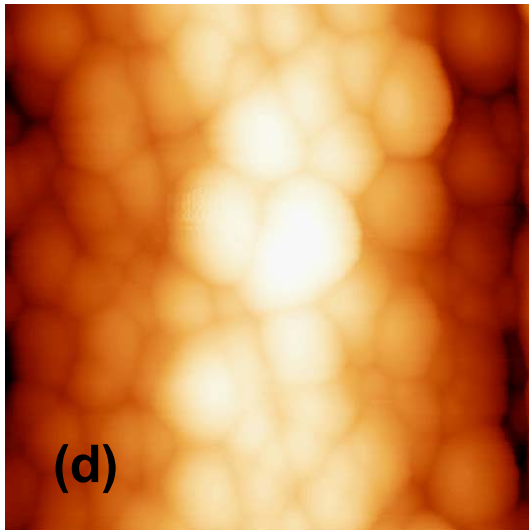
25 x 25 μm^2



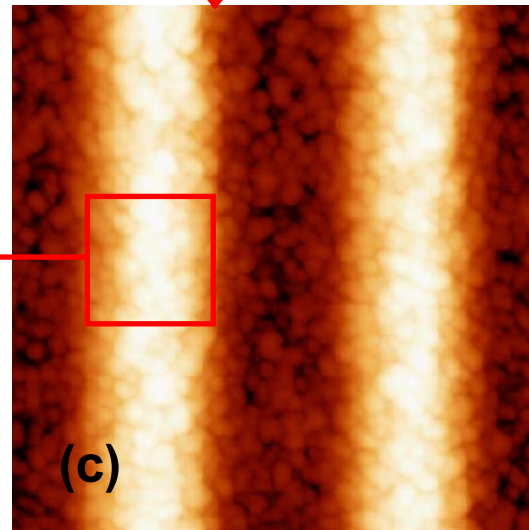
15 x 15 μm^2



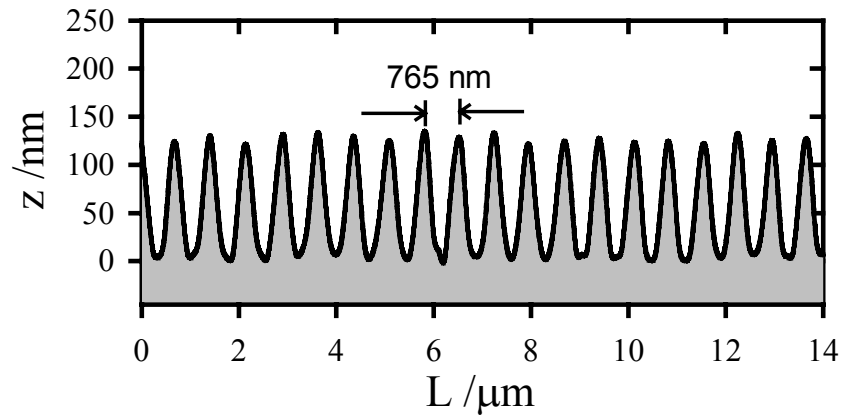
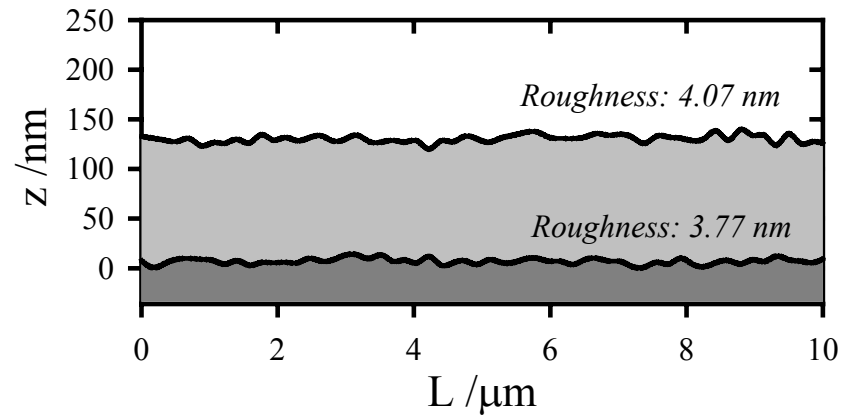
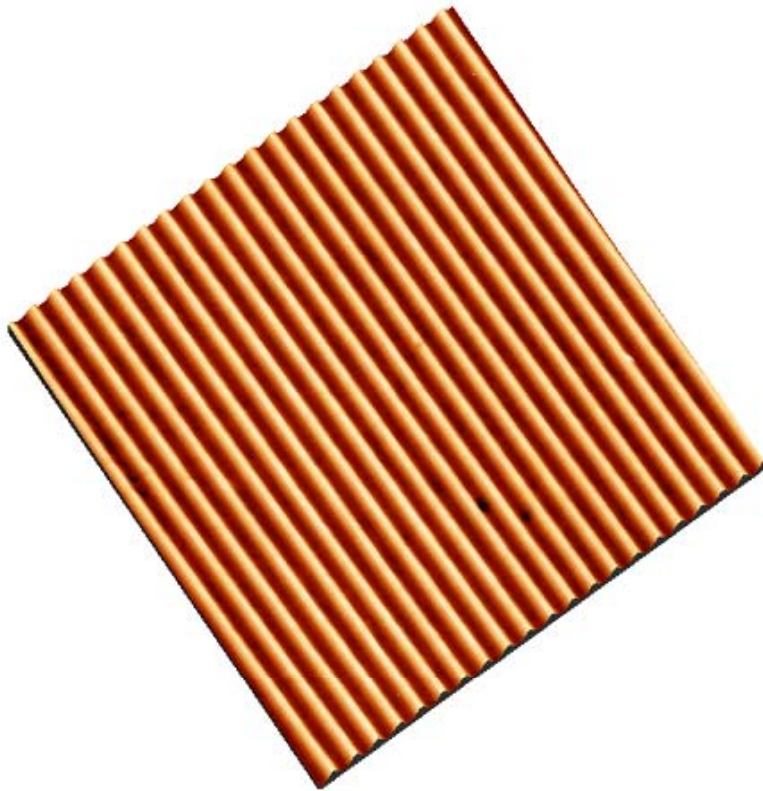
500 x 500 nm^2



1,5 x 1,5 μm^2

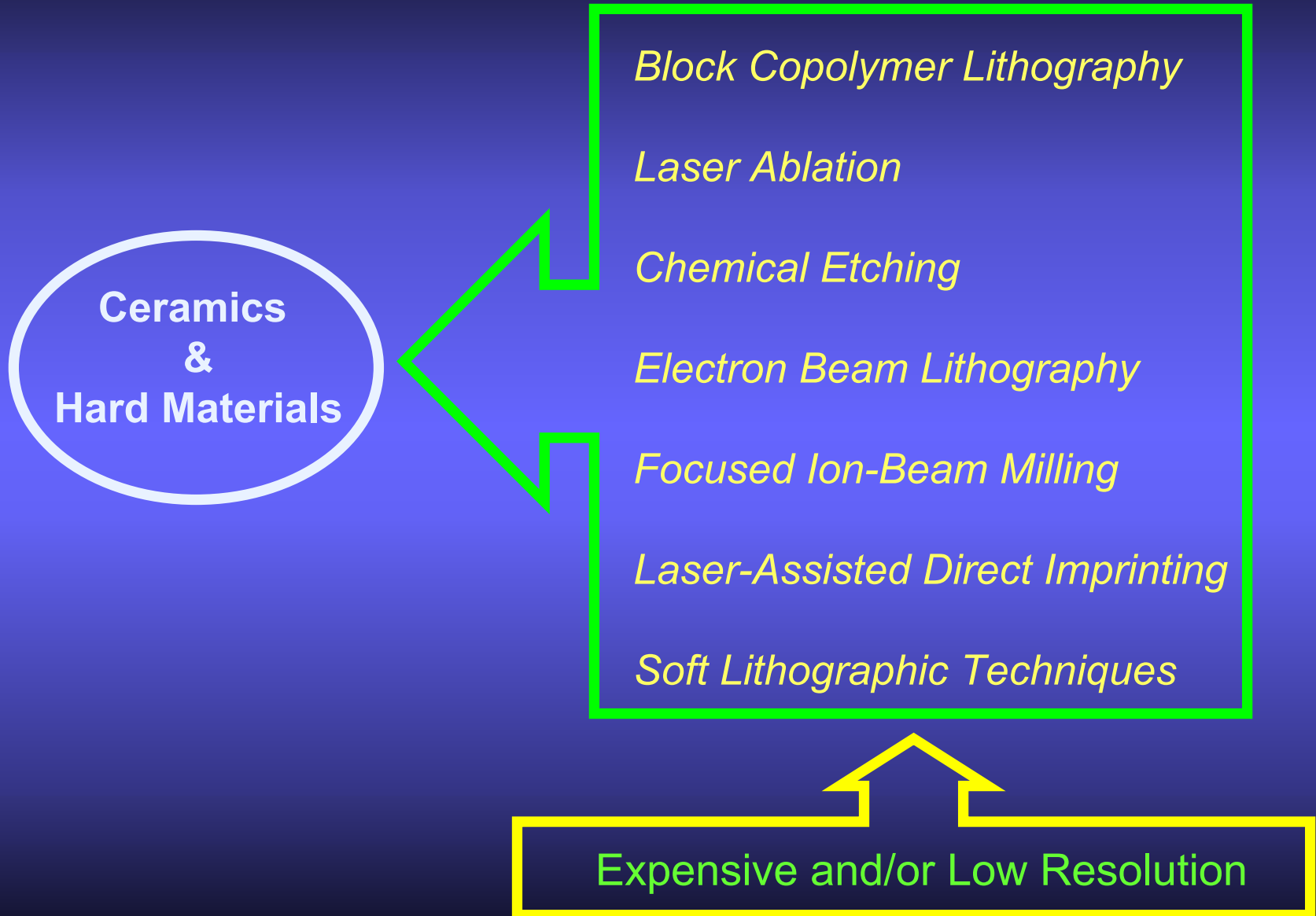


Micromolded Pulsed-Laser Deposited ZnO Surface



AFM image ($15 \times 15 \mu\text{m}^2$)

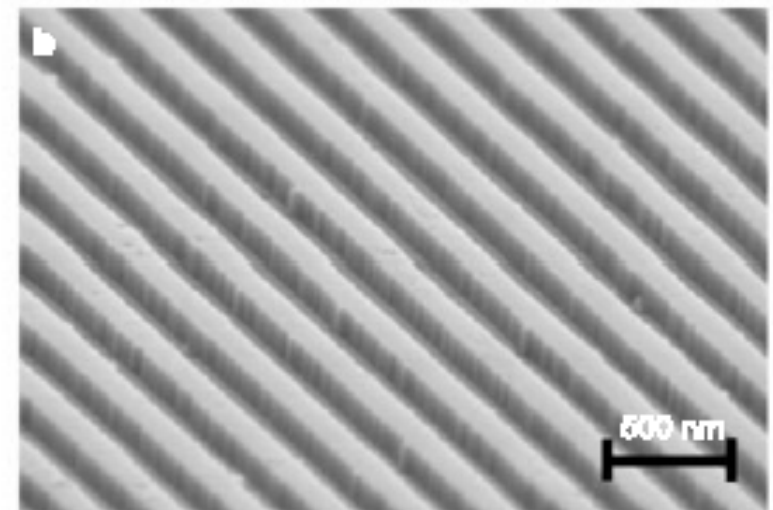
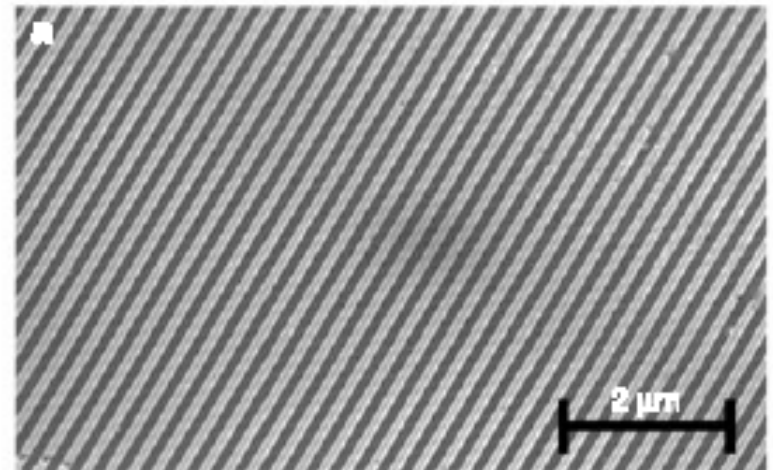
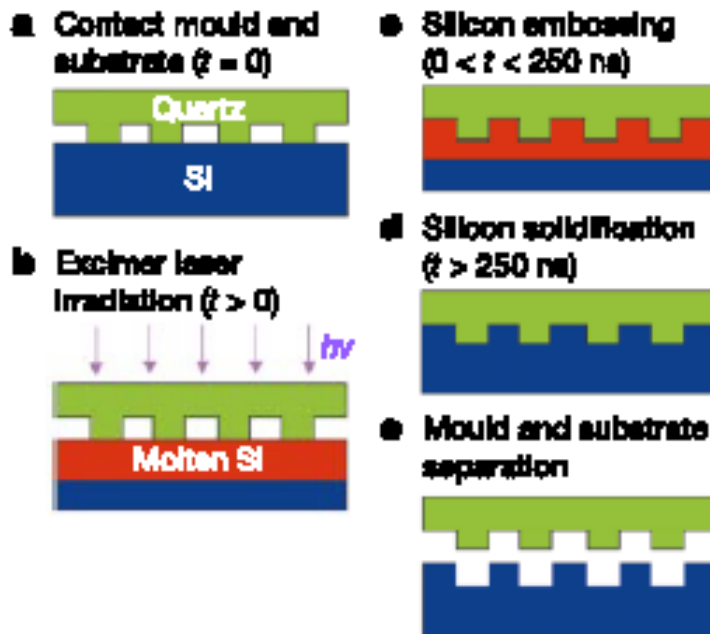
Common Strategies for Patterning Ceramics and Hard Materials



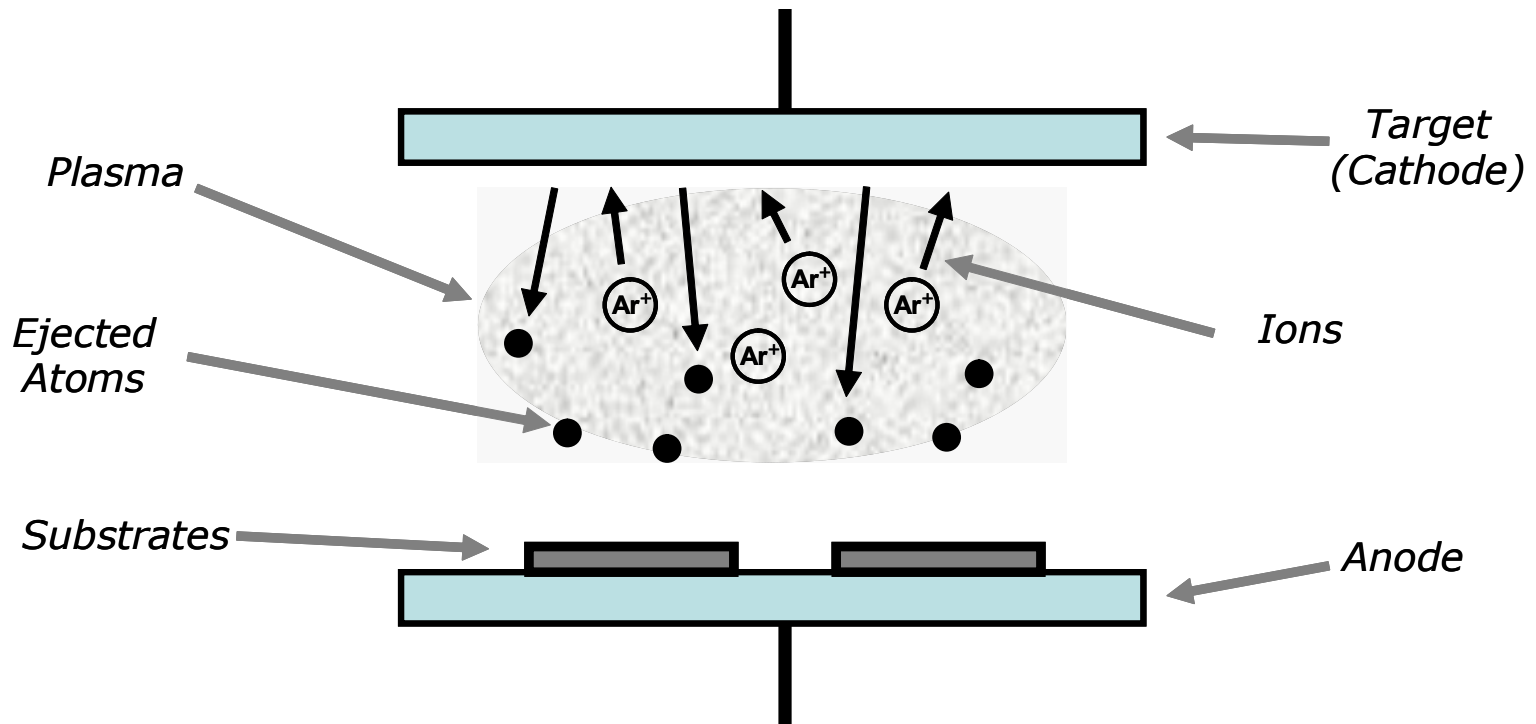
Ultrafast and direct imprint of nanostructures in silicon

Stephen Y. Chou*, Chris Keimel & Jian Gu

NanoStructure Laboratory, Department of Electrical Engineering, Princeton University, Princeton, New Jersey 08544, USA

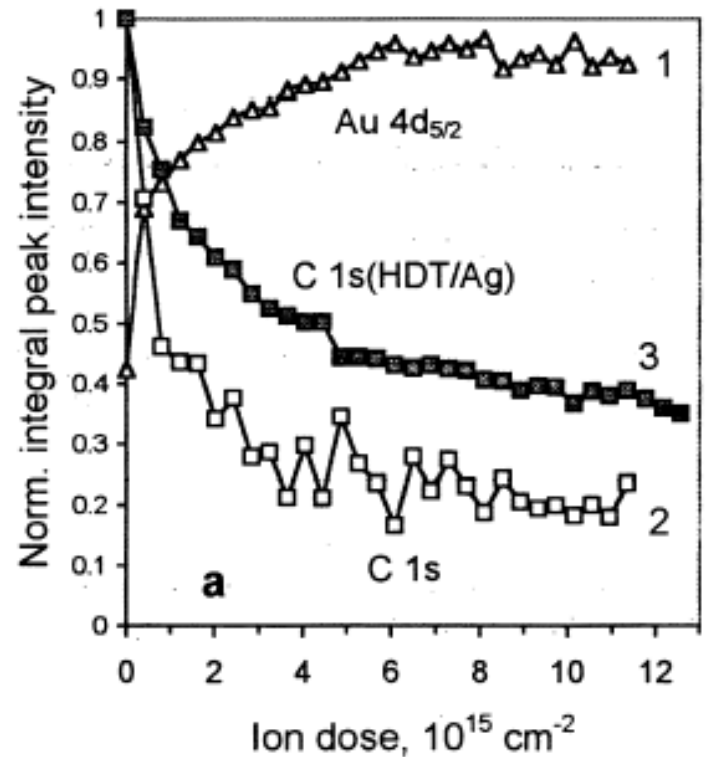
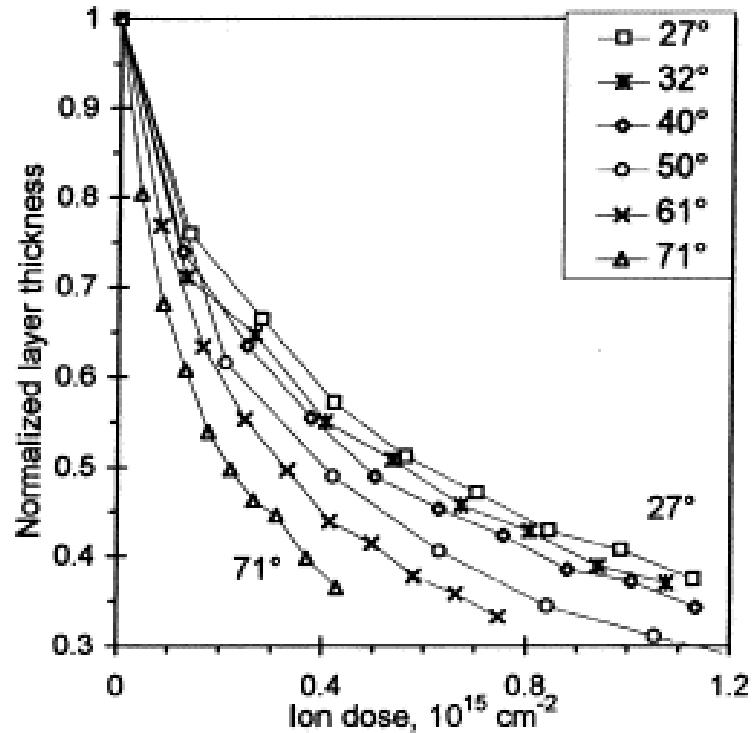


Ceramic Films Deposited by Reactive Sputtering



Sputtering of self-assembled monolayers

Collision of energetic species damages severely the self-assembled molecular film.



***Reactive Sputtering Deposition Onto
Self-Assembled Monolayers***



What Kind of Precautions Do We Have to Take Into Account ?



***Energetic Sputtered Species Colliding on the Substrate
Could Damage Severely the Self-Assembled Monolayer***



***Increase the Substrate-Target Distance And Thermalize
the Sputtered Species with the Inert Gas***

Reactive Magnetron Sputtering Conditions:

Planar Configuration → Target-Substrate Distance: ~~65 mm~~ 265 mm

Titanium Nitride (TiN)

Gas Flow (Ar + N₂) = 11 sccm (93 % Ar + 7 % N₂)

Stoichiometric Ratio (N/Ti) = 0.992

Total Pressure (P_{Ar} + P_{N2}) = 2.10⁻³ mbar

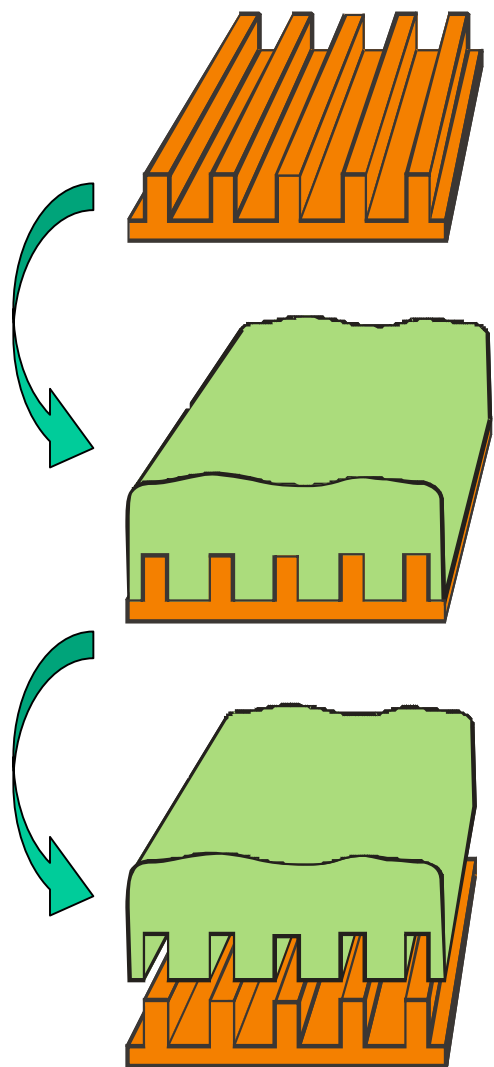
Aluminum Nitride (AlN)

Gas Flow (Ar + N₂) = 29.5 sccm (20 % Ar + 80 % N₂)

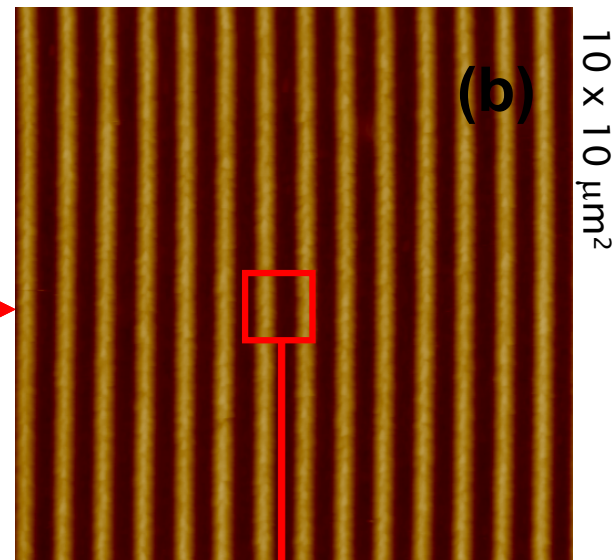
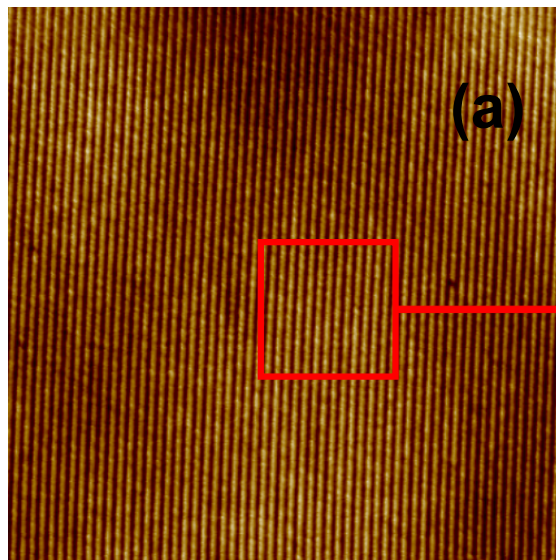
Stoichiometric Ratio (N/Al) = 0.987

Total Pressure (P_{Ar} + P_{N2}) = 4.10⁻³ mbar

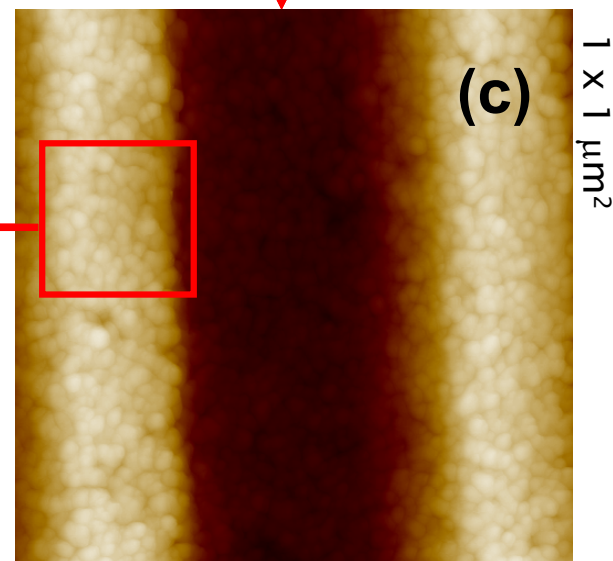
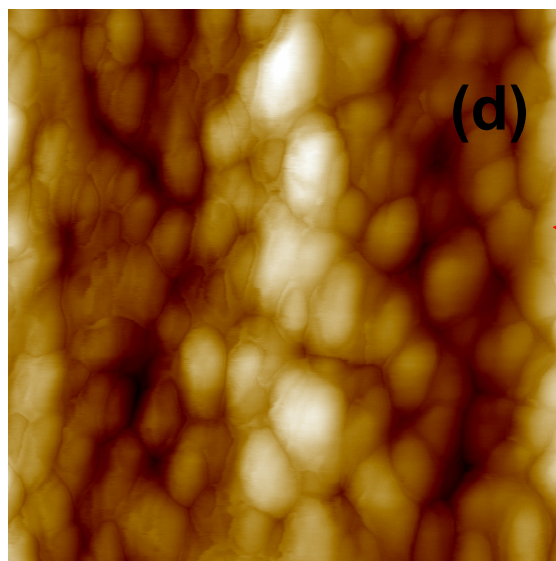
Micromolded Titanium Nitride (TiN) Surface



45 x 45 μm^2

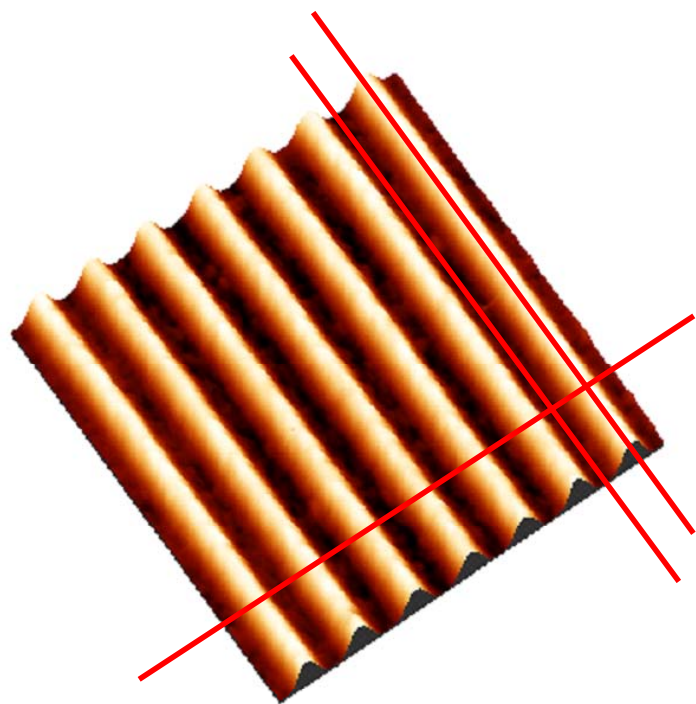


300 x 300 nm^2



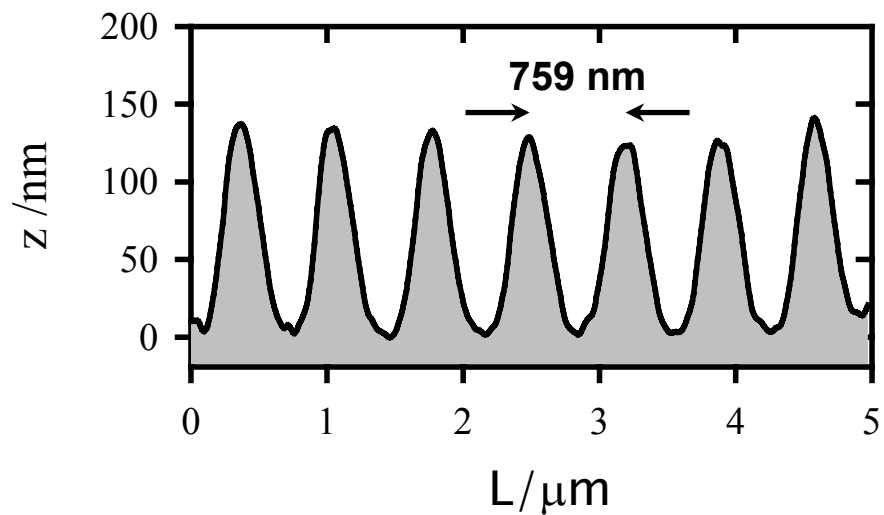
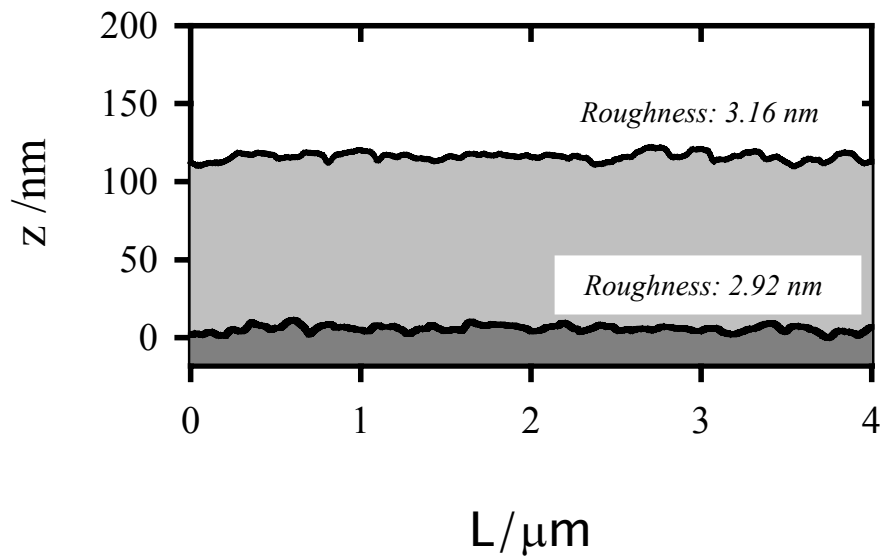
TM-AFM Images

Titanium Nitride

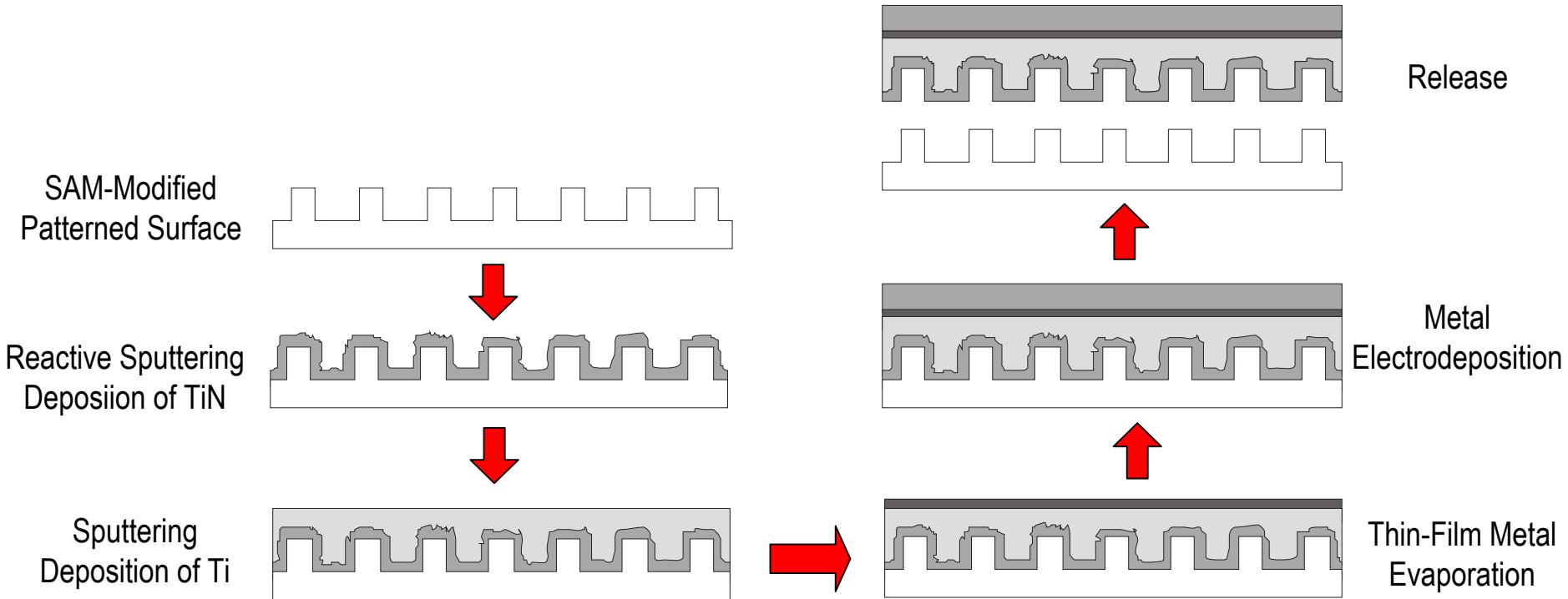


14-15 GPa

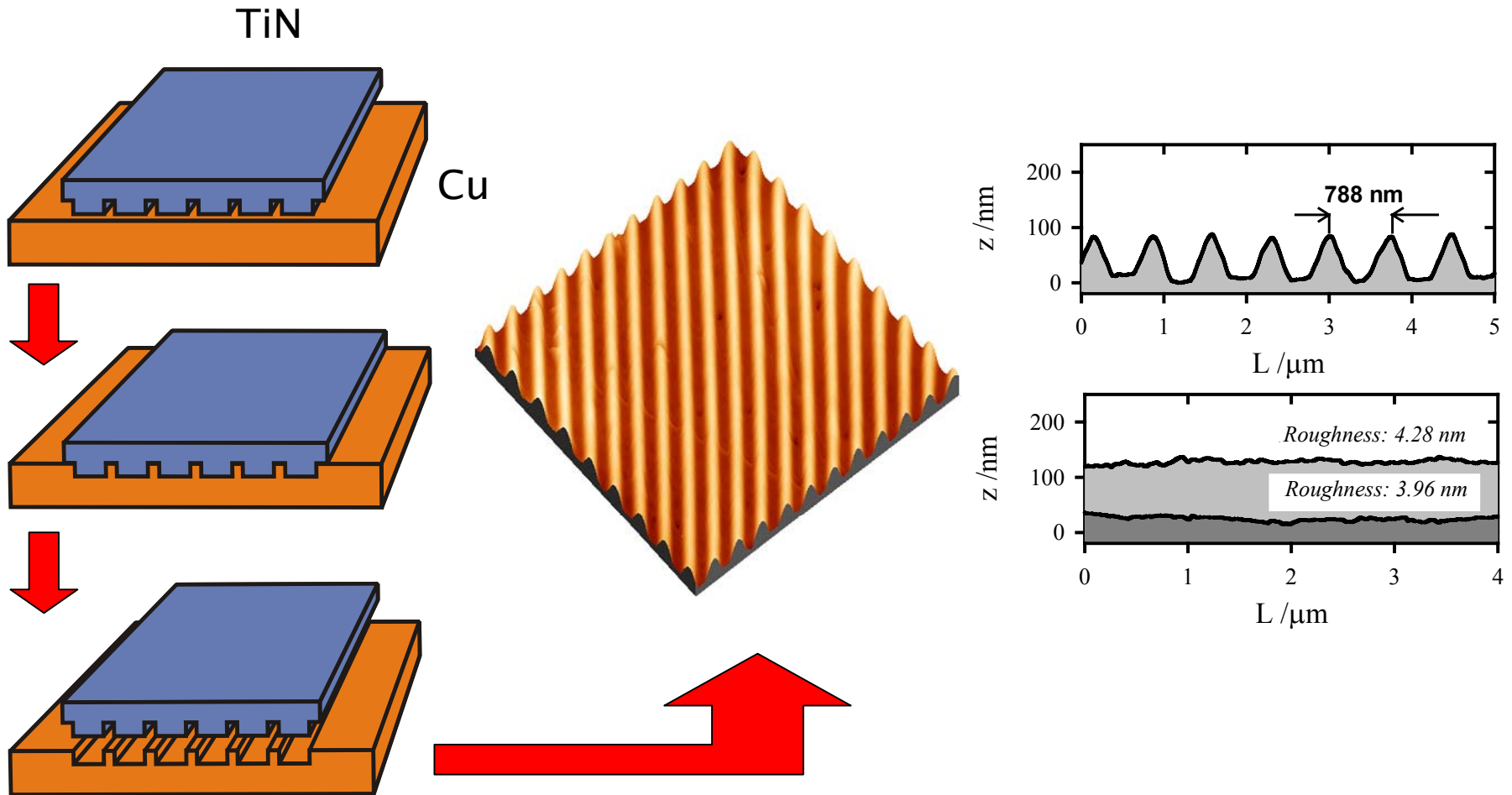
AFM image ($5 \times 5 \mu\text{m}^2$)



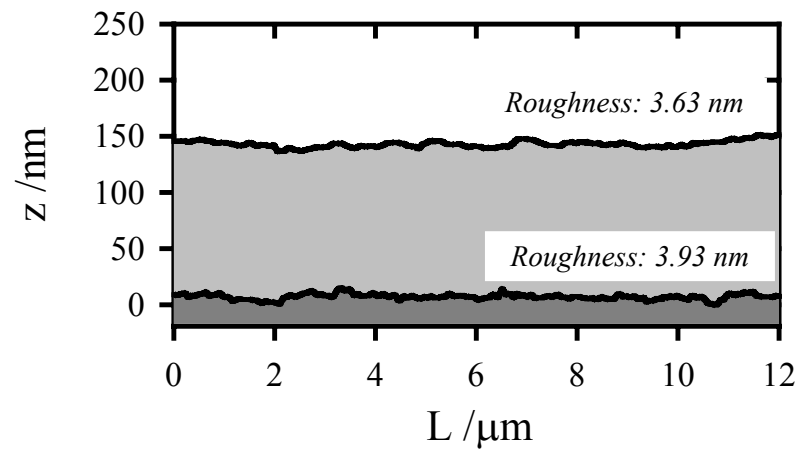
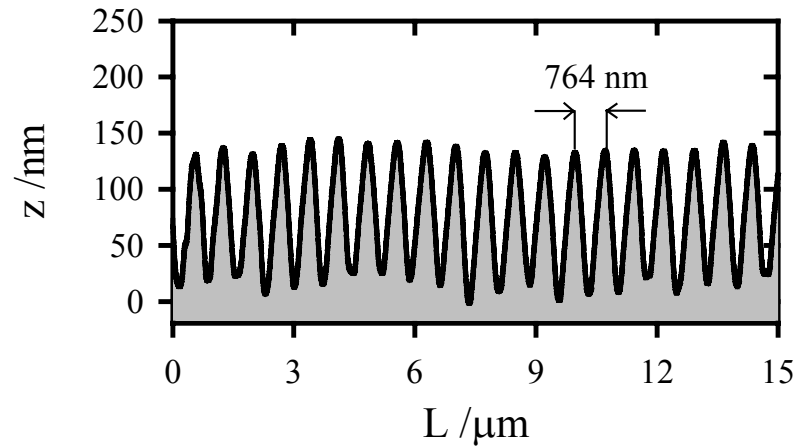
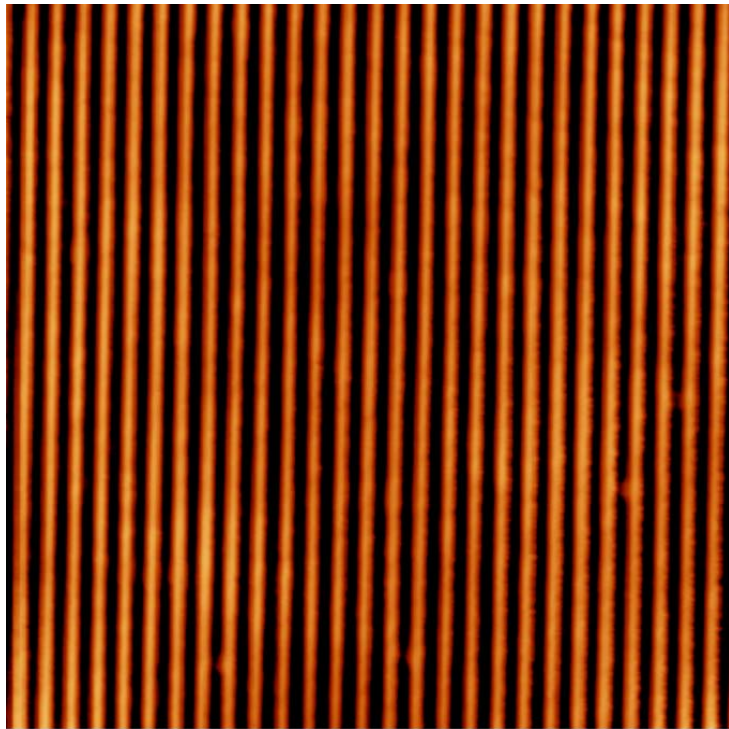
Fabrication of a TiN-made “Imprinting Stamp”



Patterned Ceramic Surfaces as Imprinting Tools



Micromolding of Aluminum Nitride (AlN) Surfaces



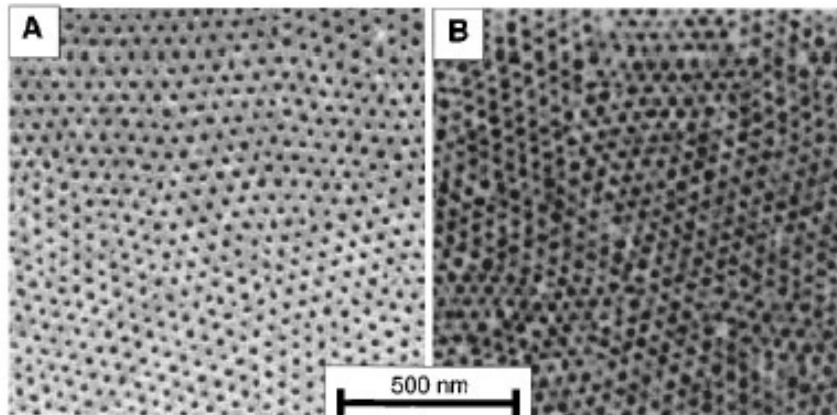
AFM image ($20 \times 20 \mu\text{m}^2$)

Strategies for Nanostructuring Ceramic Surfaces

Patterning with Nanoscale Accuracy

Block Copolymer Lithography: Periodic Arrays of $\sim 10^{11}$ Holes in 1 Square Centimeter

Miri Park, Christopher Harrison, Paul M. Chaikin,
Richard A. Register, Douglas H. Adamson

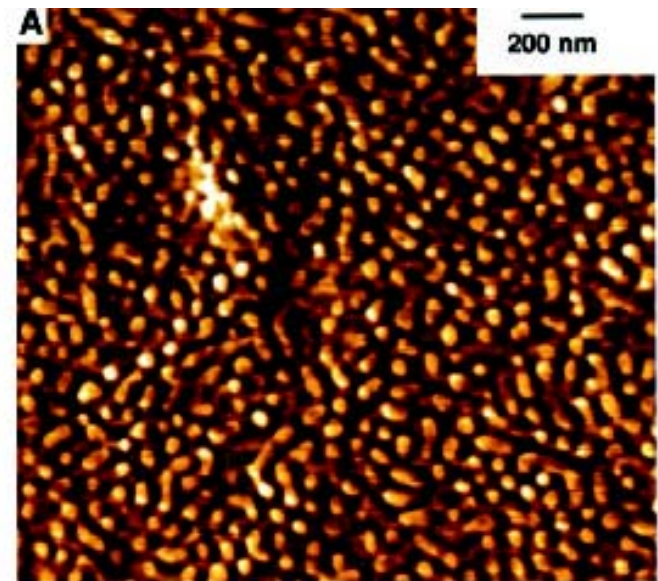


Silicon Nitride

Science, **276** (1997) 1401

Ordered Bicontinuous Nanoporous and Nanorelief Ceramic Films from Self Assembling Polymer Precursors

Vanessa Z.-H. Chan,¹ James Hoffman,² Victor Y. Lee,³
Hermis Iatrou,⁴ Apostolos Avgeropoulos,⁴ Nikos Hadjichristidis,⁴
Robert D. Miller,³ Edwin L. Thomas^{1*}



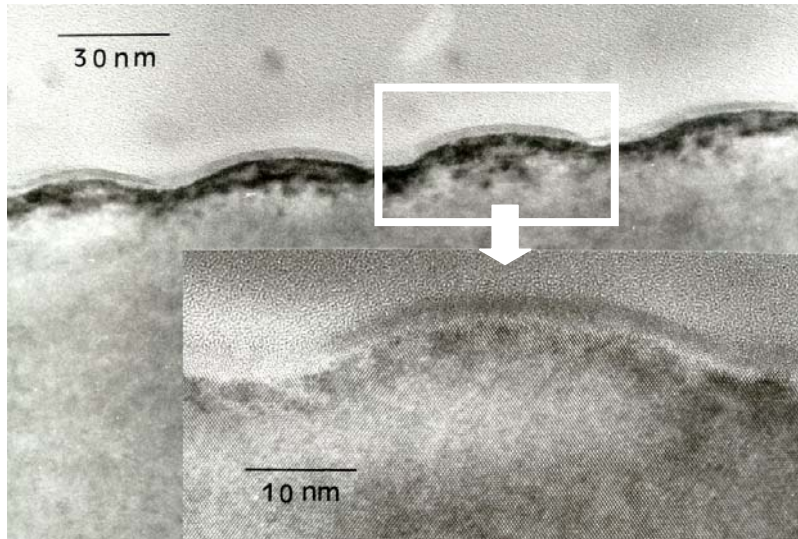
Silicon Oxycarbide

Science, **286** (1999) 1716

Master Nanofabrication by Low-Energy Ion-Beam Sputtering

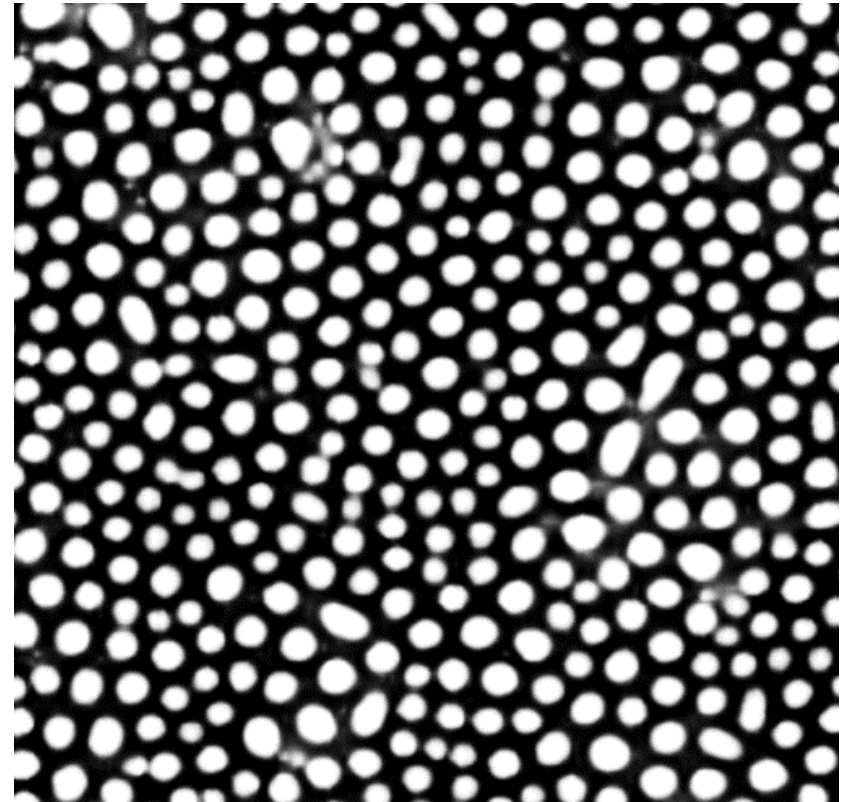
n-type Si(100) substrates
Ar⁺ bombardment (normal incidence)
at 1 keV and 0.24 mA

TEM

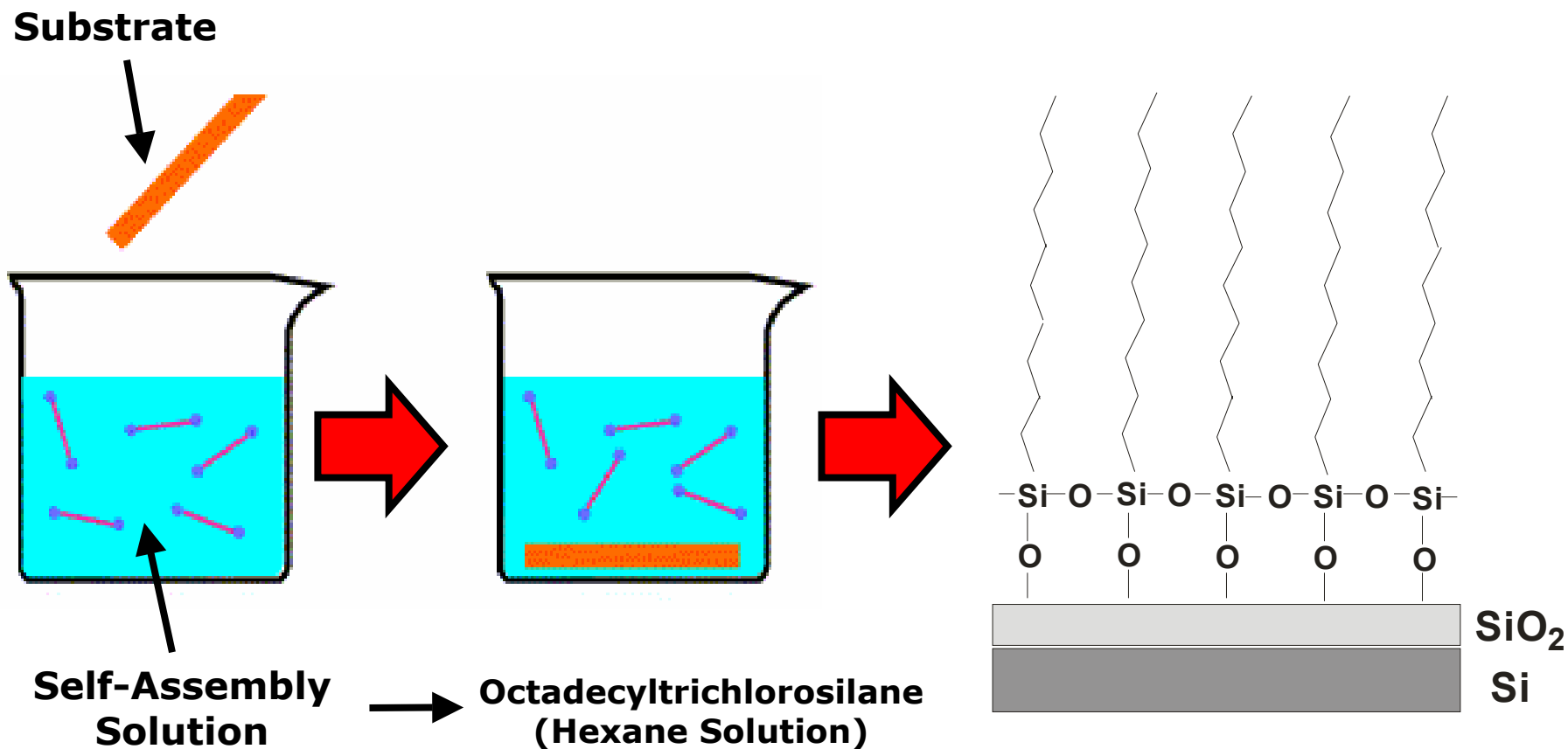


TM-AFM

1 x 1 μm²

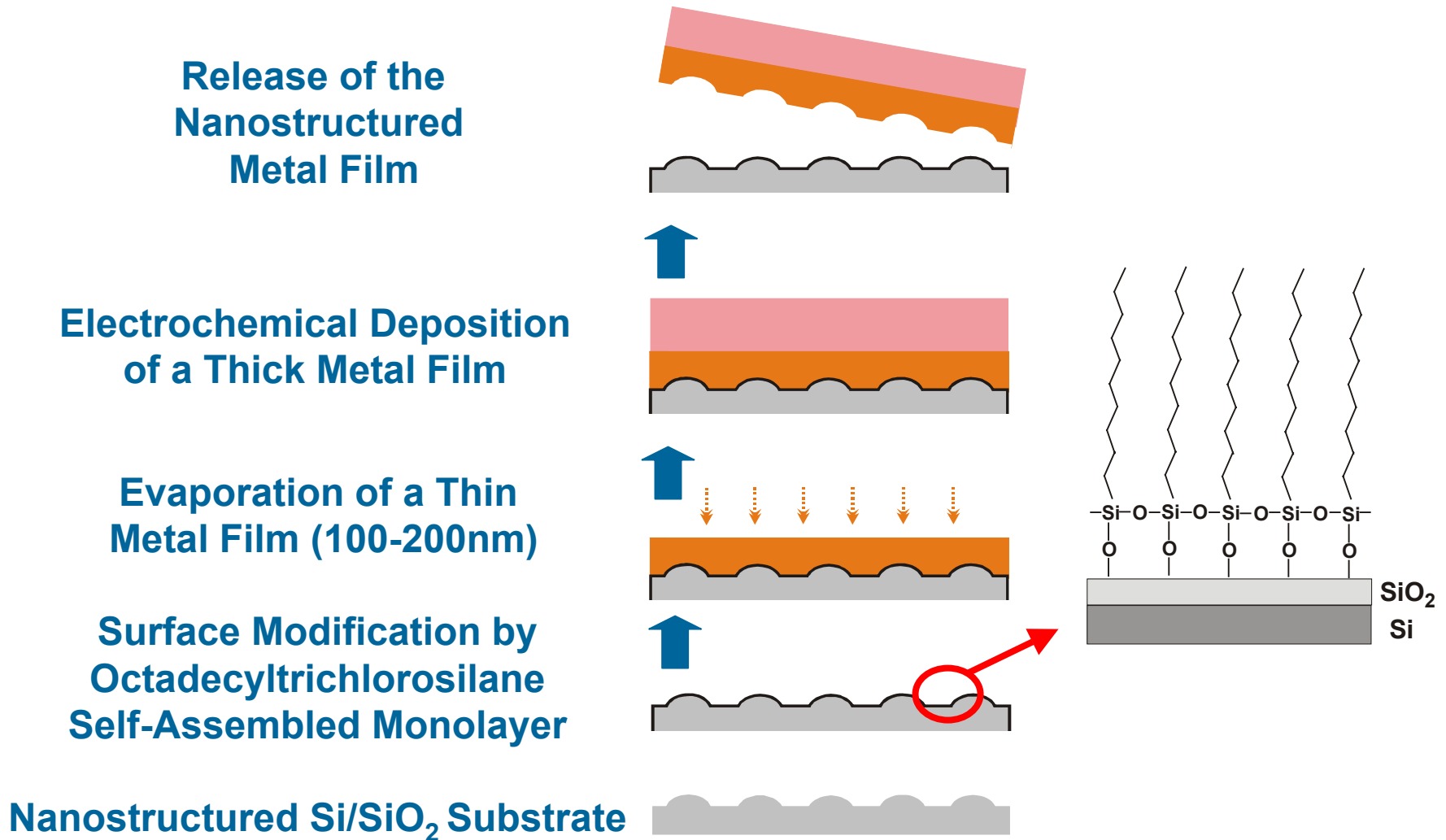


Long-Chain Silane Self-Assembled Monolayers as Anti-Sticking Molecular Coatings



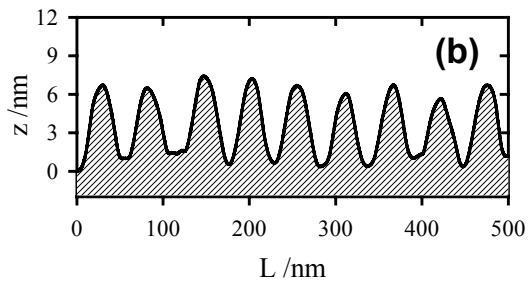
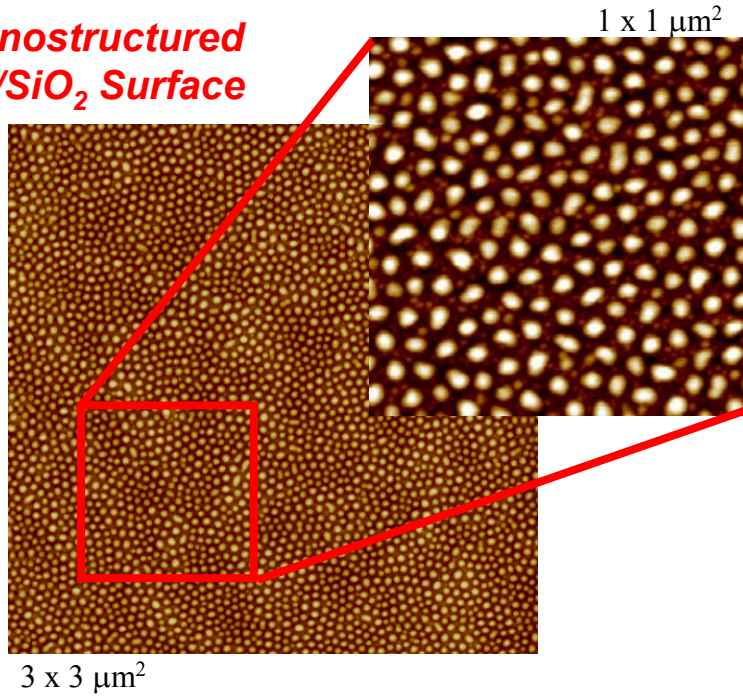
Replication at the nanometer scale.

Building-up the metal nanomolds by thermal evaporation

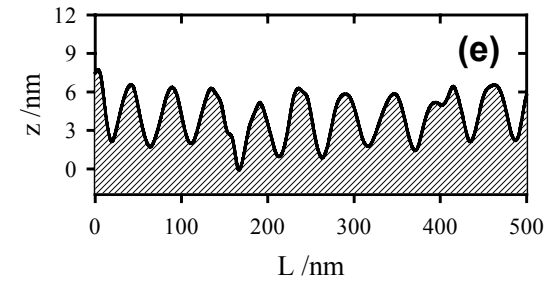
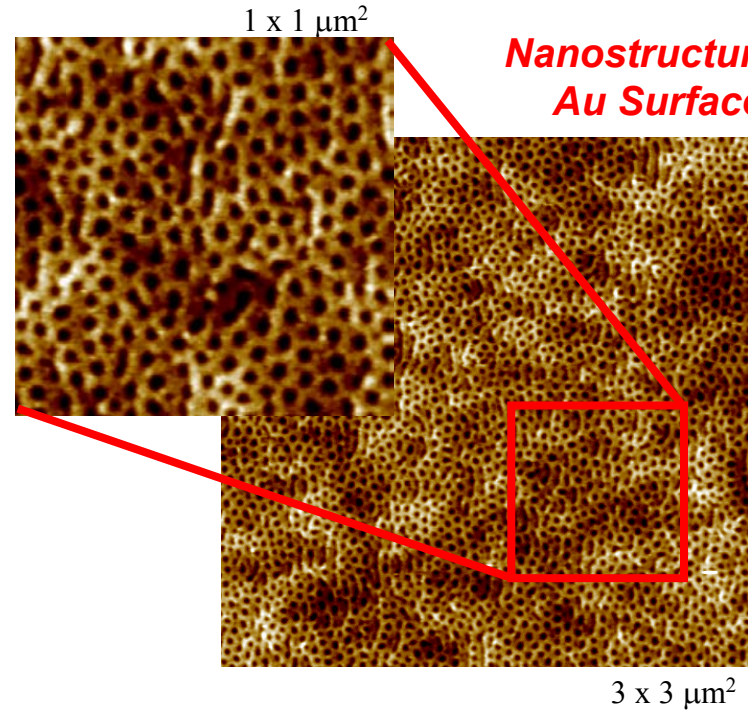


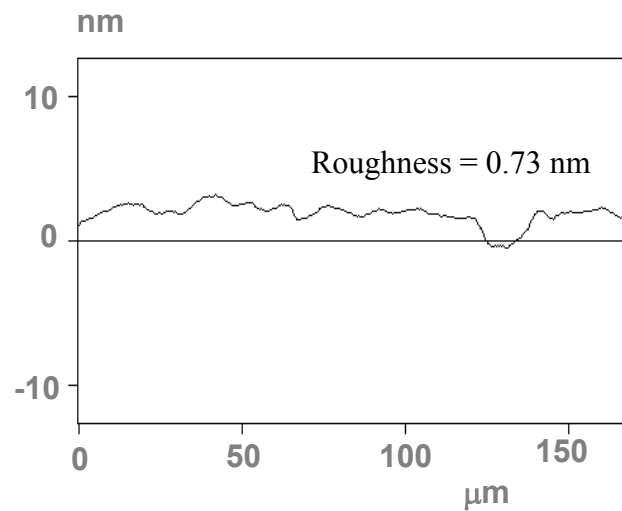
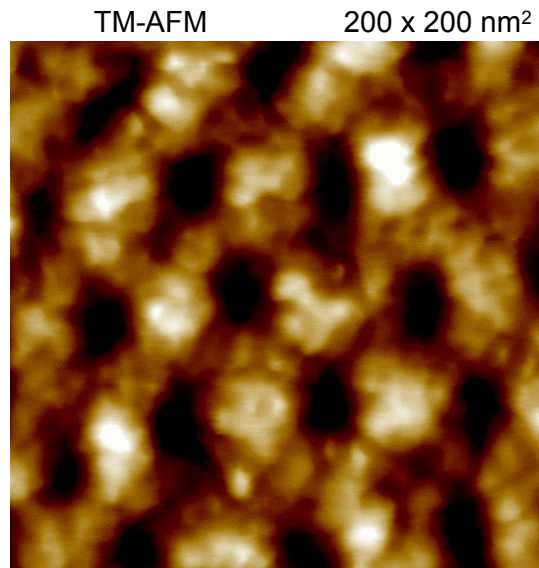
Fabrication of Metal Nanomolds

**Nanostructured
Si/SiO₂ Surface**

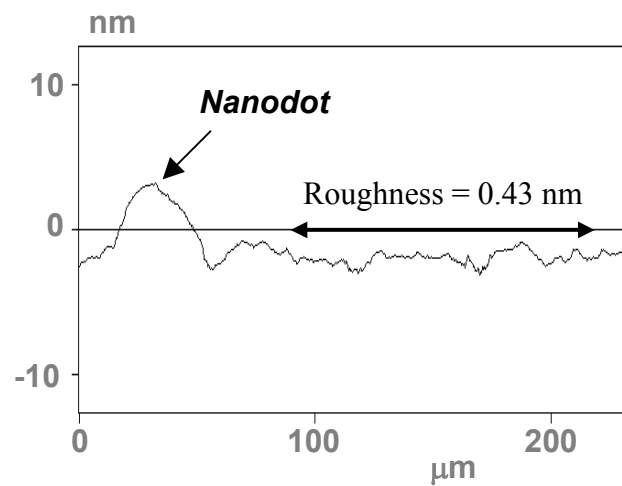
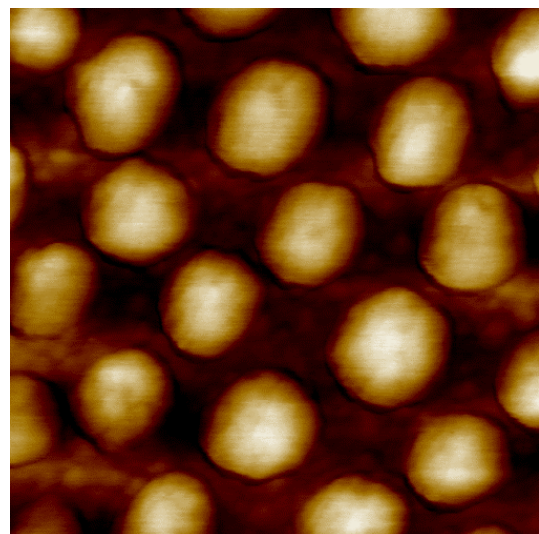


**Nanostructured
Au Surface**





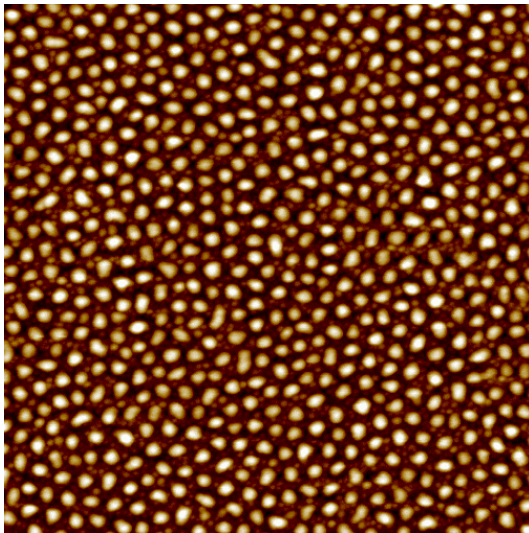
Au



Si/SiO₂

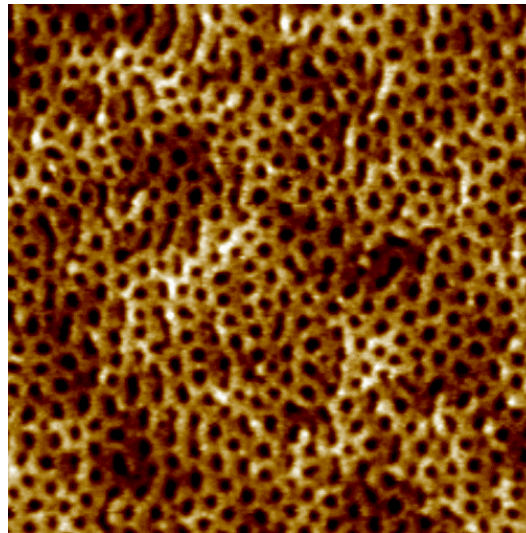
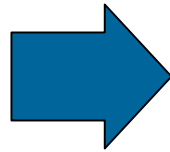
TM-AFM 200 x 200 nm²

Nanoscale Replication on Ceramic Materials



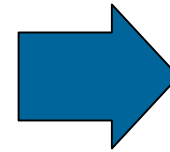
1 x 1 μm^2

Nanostructured
Si/SiO₂ Master Surface

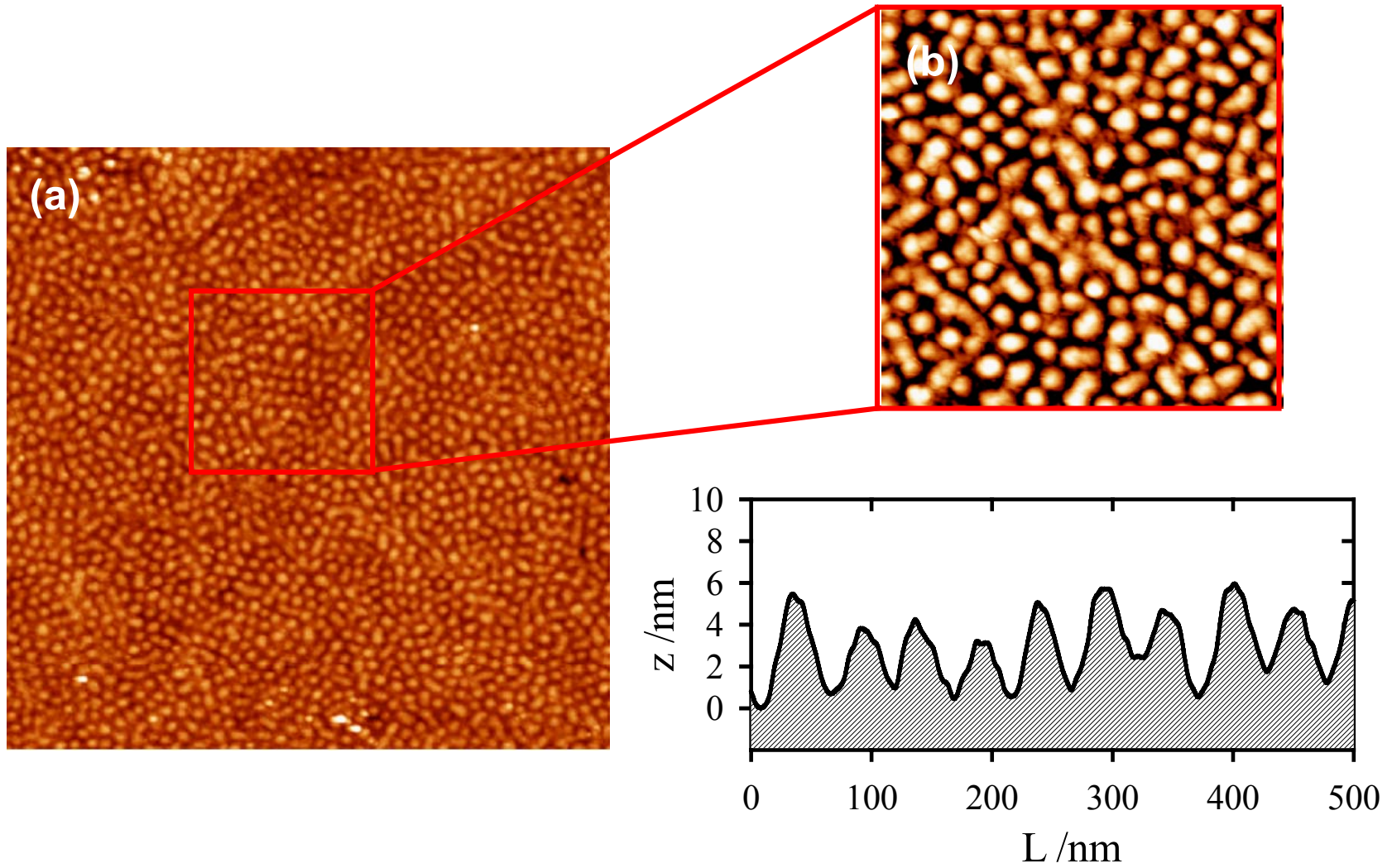


1 x 1 μm^2

Gold-Made Nanomold

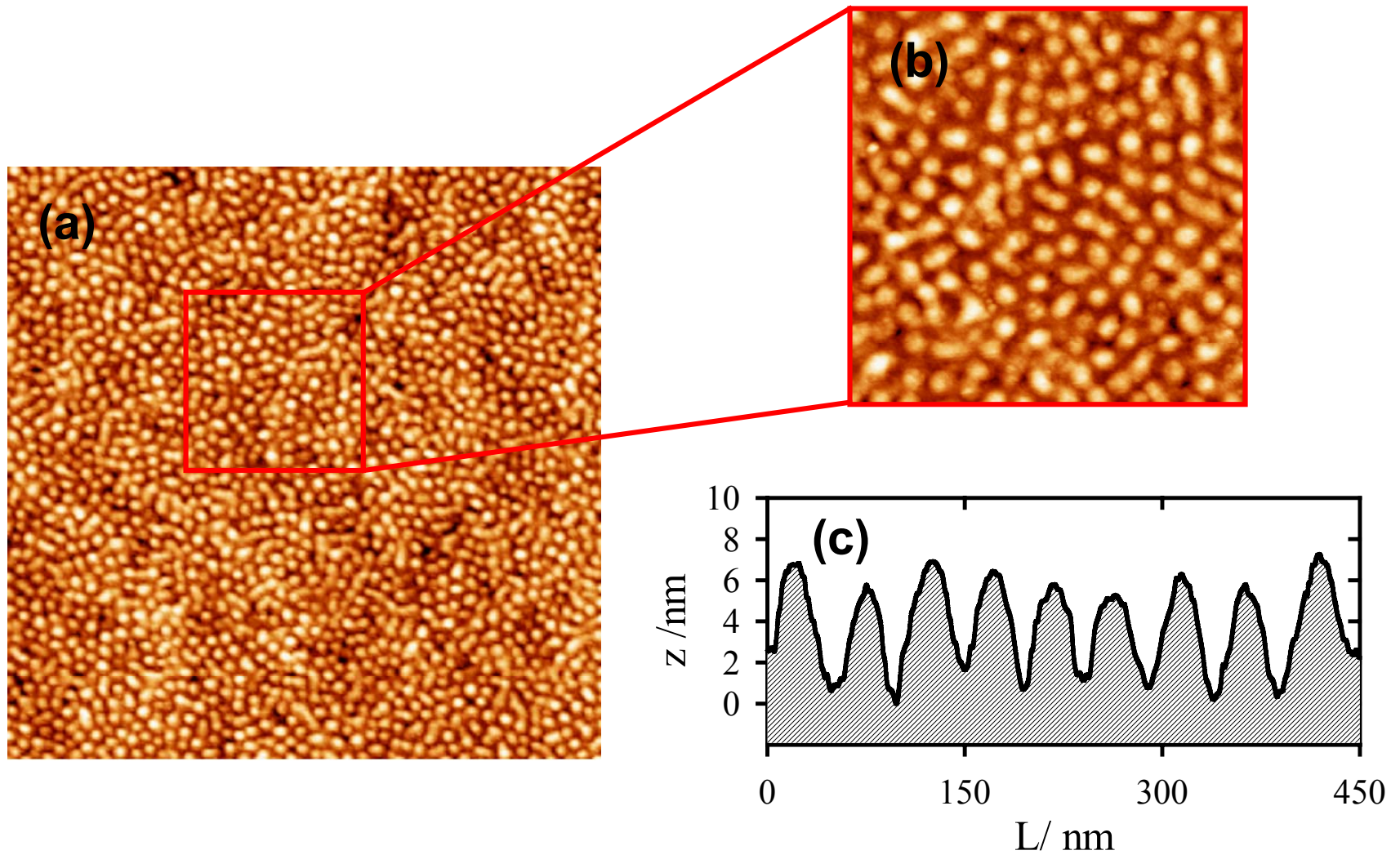


Nanoreplicated Titanium Nitride (TiN) Surface



AFM Images: (a) $2 \times 2 \mu\text{m}^2$ (b) $600 \times 600 \text{ nm}^2$

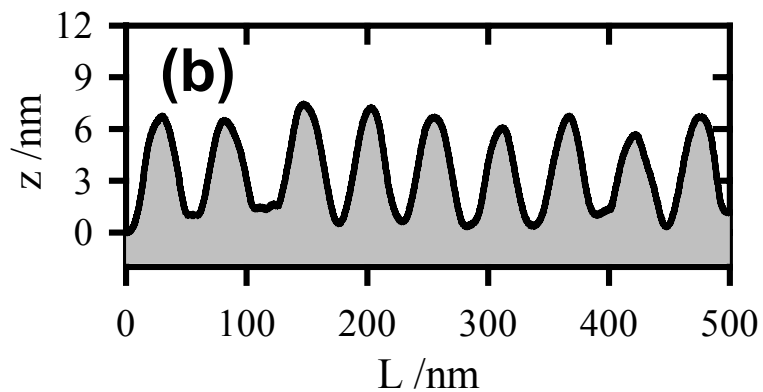
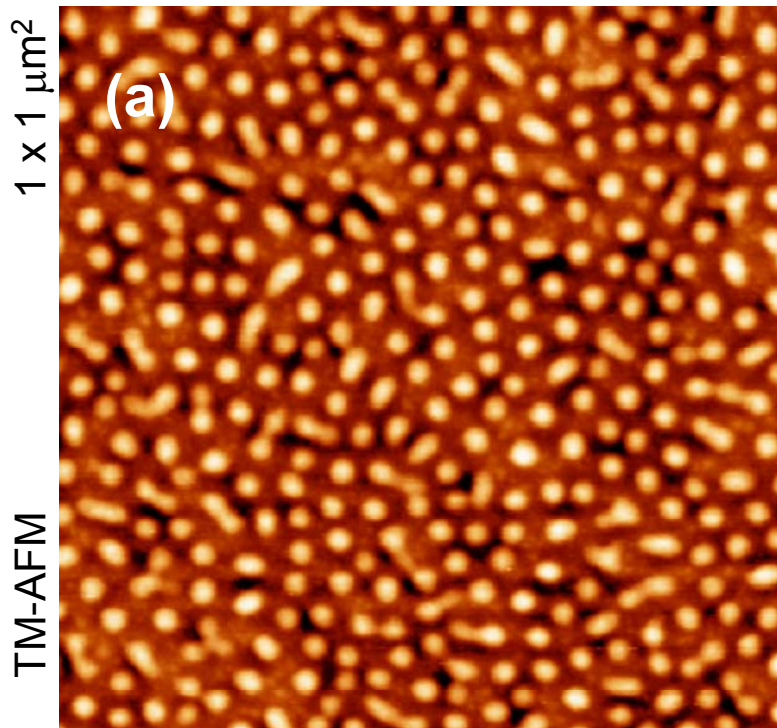
Nanoreplicated Aluminum Nitride (AlN) Surface



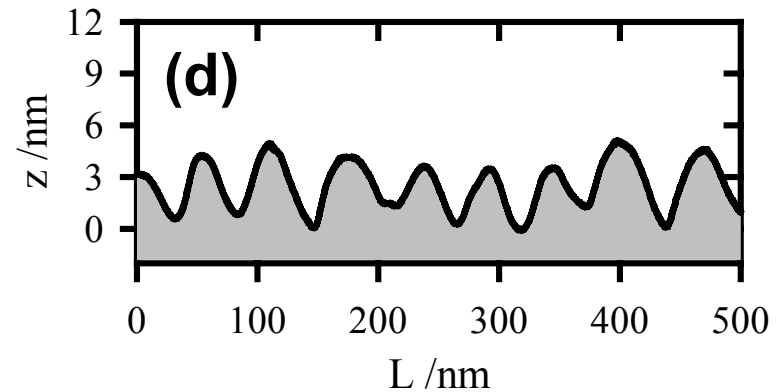
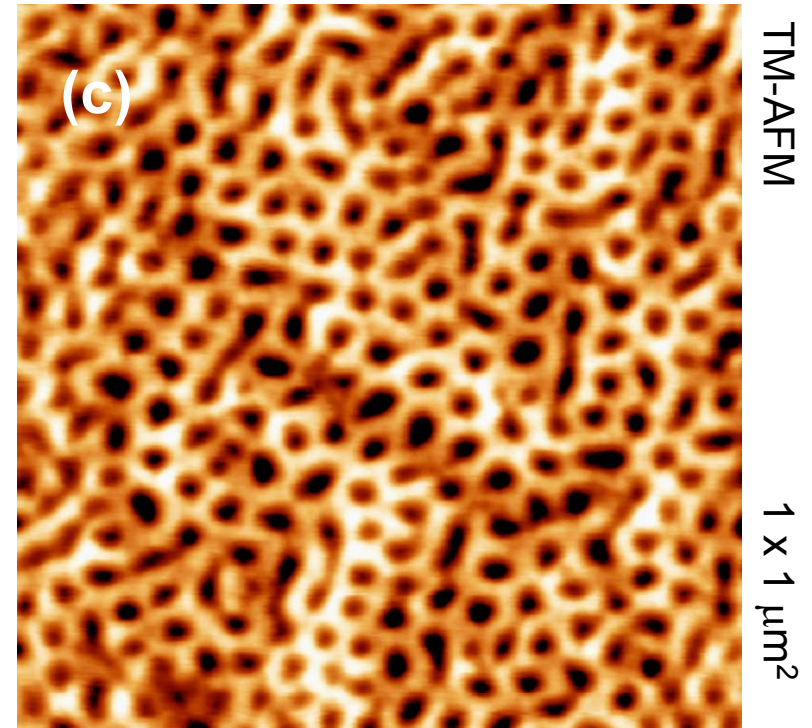
AFM Images: (a) $2 \times 2 \mu\text{m}^2$ (b) $600 \times 600 \text{ nm}^2$

Direct Molding of Nanostructured Ceramic Surfaces

SiO_2/Si



Titanium Nitride



Conclusions

- * Molding and replication techniques, commonly used for patterning polymeric materials, can be successfully extended to a wide range of materials.
- * By using conductive “stamps” it is possible to exploit the advantages of soft lithographic techniques for patterning materials that can be electrodeposited.
- * Molding and replication techniques can be used for transferring surface–relief patterns onto different materials, from metals to ceramics, with nanoscale resolution.
- * When dealing with “electrochemical” soft lithography using conductive stamps, the self–assembled monolayer plays a key role as “release agent” during the replica–molding process. Its electrochemical stability determines the feasibility of the process.
- * The same SAM–modified conductive “stamps” can be used for patterning other materials that can be deposited by pulsed laser ablation or reactive sputtering.
- * Deposit grain size is a variable that influences the fidelity of the molding process, and it must be taken into account when the deposition technique is chosen.

Acknowledgements

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